



TBA

Edoardo Vicentini

CIC nanoGUNE

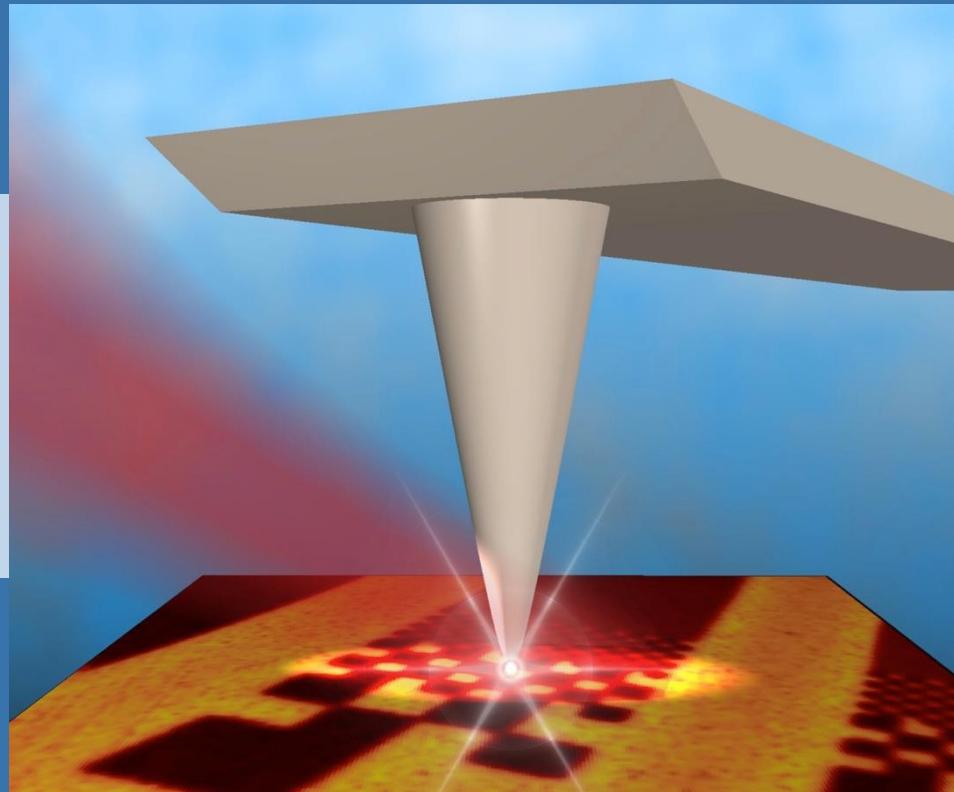
San Sebastian, Spain

# Infrared nanoimaging and nanospectroscopy by near-field optical microscopy

Edoardo Vicentini

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# San Sebastian - Donostia



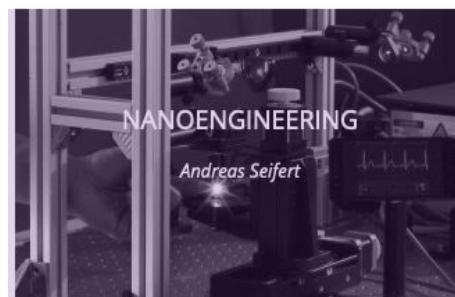
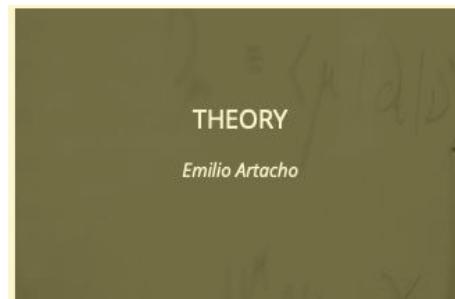
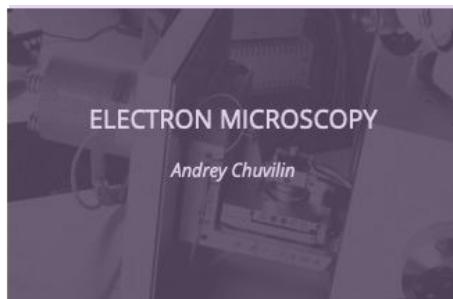
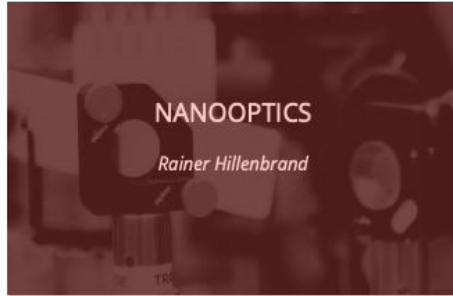
# San Sebastian - Donostia



# CIC nanoGUNE



# CIC nanoGUNE



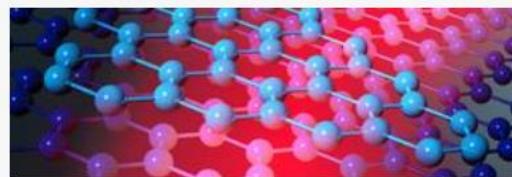
# NANOOPTICS group

## INSTRUMENTAL DEVELOPMENTS



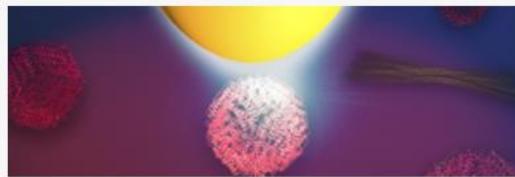
We continuously work on novel instrumental developments, with the goal to push the spatial resolution towards the single molecule level and to enable three-dimensional infrared-spectroscopic nanotomography.

## PLASMONICS AND PHONONICS



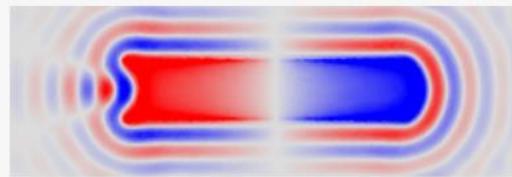
We apply s-SNOM and nano-FTIR to study plasmons in metal and graphene nanostructures, as well as phonons in polar crystals, for the development of ultracompact nanophotonic devices and their application, e.g. in optoelectronics and sensing.

## IR NANOSPECTROSCOPY



IR s-SNOM and nano-FTIR are applied for nanoscale mapping of chemical composition of polymers, secondary structure of proteins, carrier distribution in semiconductor nanowires and optoelectronic properties of novel 2D materials.

## NANOOPTICS THEORY



We develop and apply theory for the propagation and scattering of waves/surface waves in natural, artificial and 2D materials, for modeling near-field spectroscopy, and for reconstruction of material properties from near-field data.

# NANOOPTICS group

## INSTRUMENTAL DEVELOPMENTS



## PLASMONICS AND PHONONICS

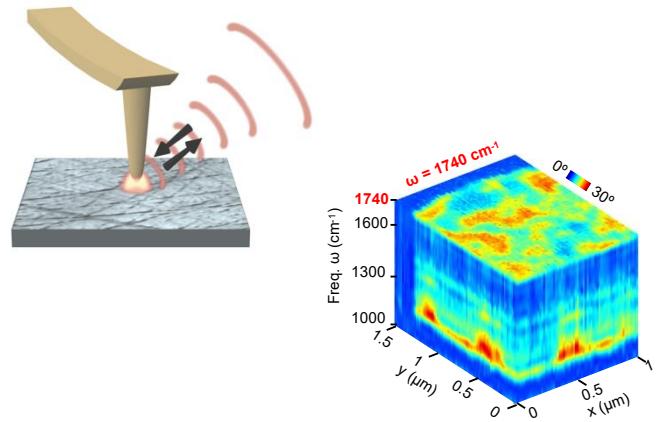




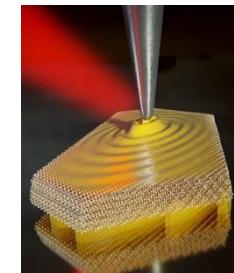
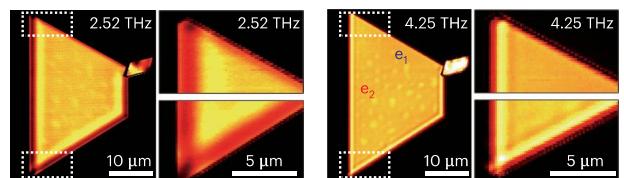
# Outline

s-SNOM and nano-FTIR techniques

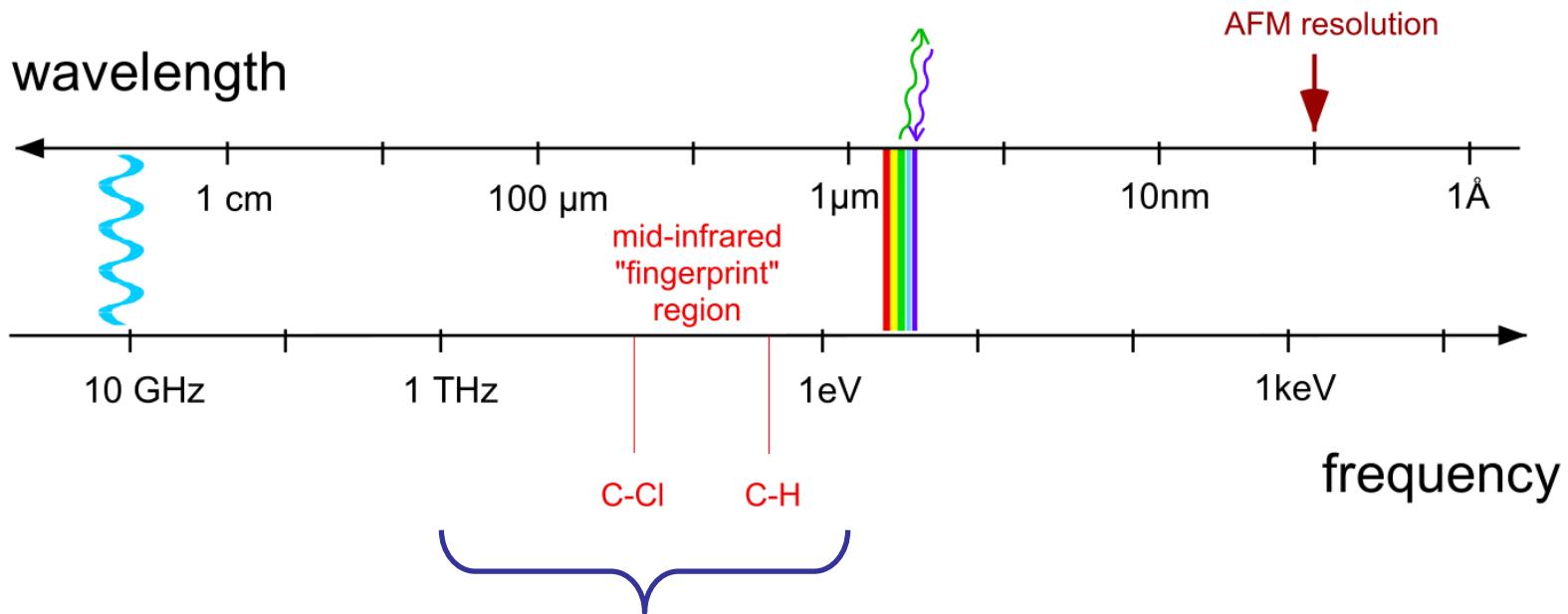
illustrated with materials characterization examples



Imaging anisotropic plasmon polaritons in AgTe by THz s-SNOM



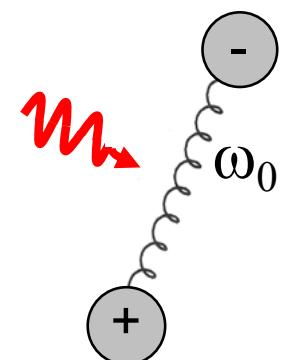
# Infrared spectroscopy is a highly sensitive tool for material analysis



IR is highly sensitive to

- molecular vibrations → chemical composition
- crystal lattice vibrations → structural properties
- plasmons in doped semiconductors, graphene → electron properties
- .....

BUT: spatial resolution is diffraction limited

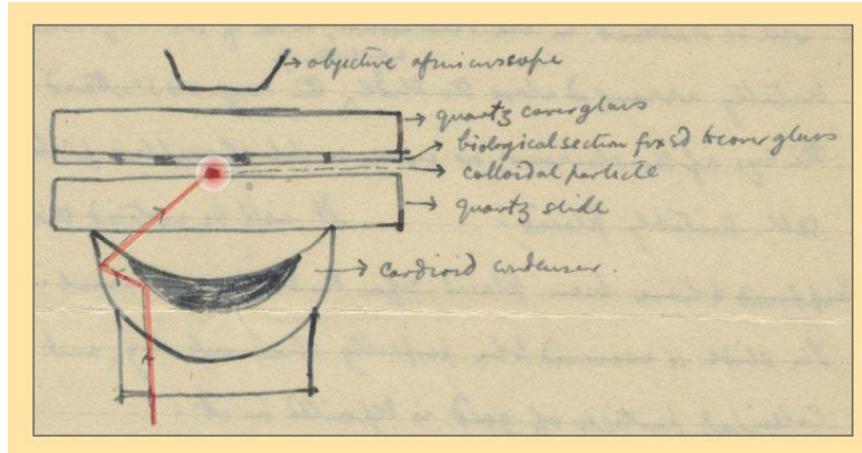




## Edward Hutchinson Synge's idea

Idea for super-resolution imaging was conceived as early as in 1928

### Original idea (1928)

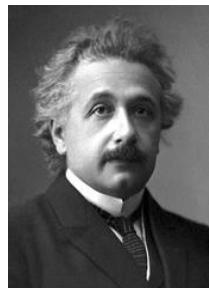
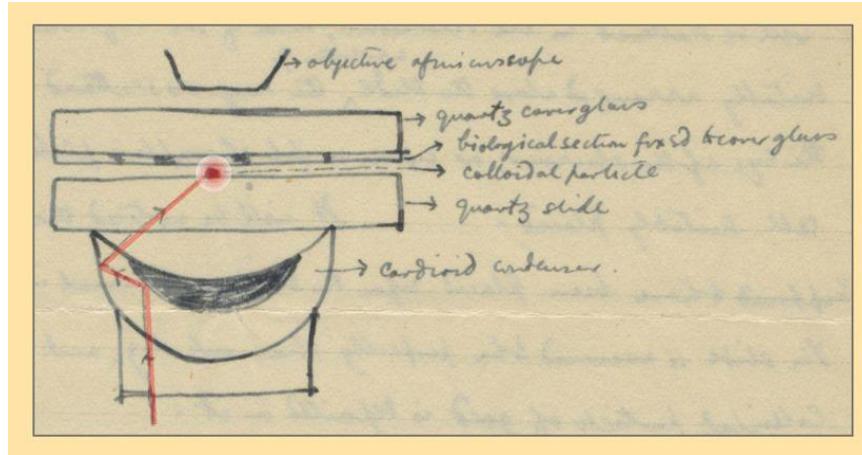




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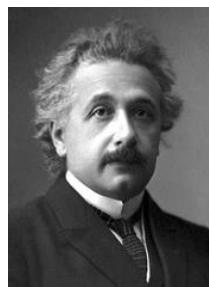
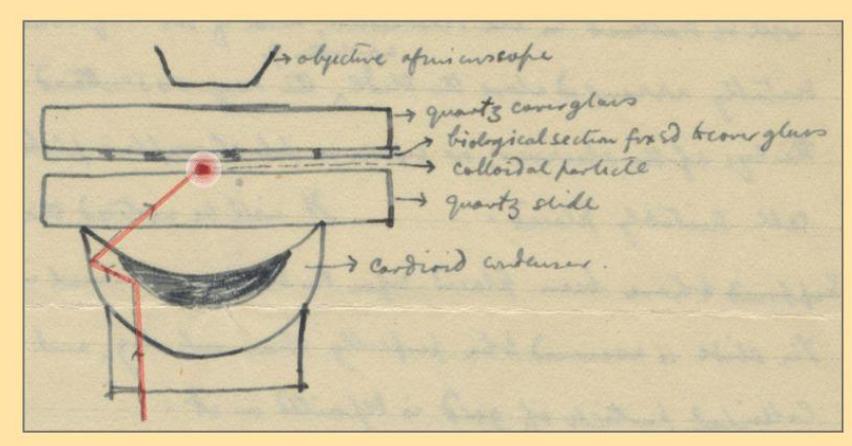
“As far as this goes, I agree. However,  
your method of implementation  
appears to be fundamentally  
unusable to me”  
1928 – Albert Einstein



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## First super-resolution imaging (1972)

NATURE VOL. 237 JUNE 30 1972

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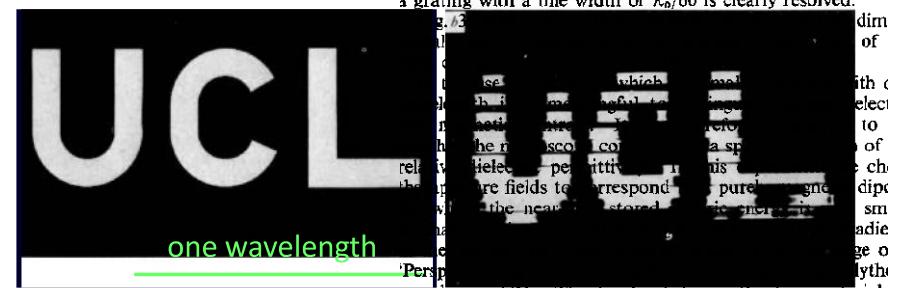
J.R.  
MCROFT

are soon frustrated, however, because the spatial frequencies one is seeking to transfer are such that the waves become evanescent in the direction in which one would like them to propagate. Nassenstein has developed an ingenious scheme<sup>3</sup> in which evanescent waves are used to illuminate the object, and a magnified image is obtained using a holographic technique. The resolution capability is determined by the wavelength of the evanescent wave. This is less than  $\lambda_0$ , but it is not easy to devise systems where it would be very much smaller.

Such approaches depend on transferring information from all the resolvable points in the object plane to the image plane simultaneously—that is, a parallel processing system. The problem of obtaining super-resolution can be simplified greatly by resorting to a scanning technique. If we can illuminate one resolution area of the object at a time, the problem of extracting the information becomes relatively simple. One cannot overcome the classical resolution limit simply by focusing a beam of radiation on to the object, because the minimum

E.A. Ash, G. Nicholls, Nature 237, 510 (1972)

using an aperture diameter  $a_{\text{ap}} = 1.2 \text{ mm}$ , in the ultra  $\epsilon$  a grating with a line width of  $\lambda_b/60$  is clearly resolved.



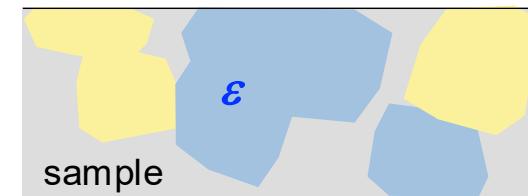
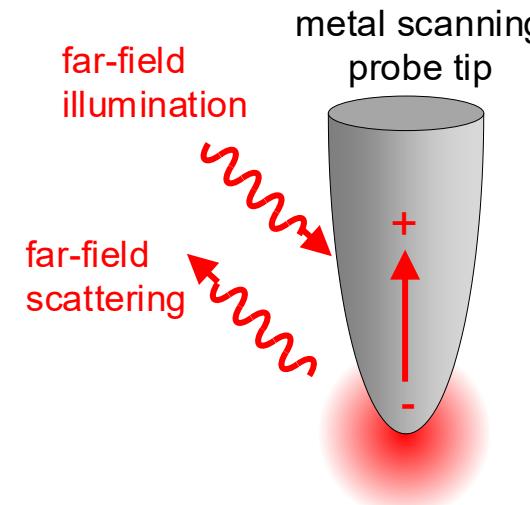
Resolution of 1/60 of the wavelength



# Modern s-SNOM

(scattering-type scanning near-field optical microscopy)

A sharp metal tip replaces the particle in Synge's idea

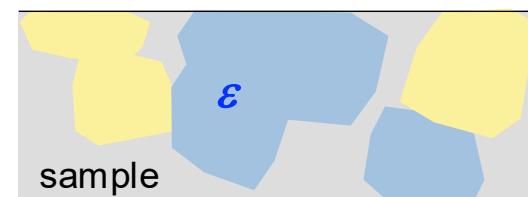
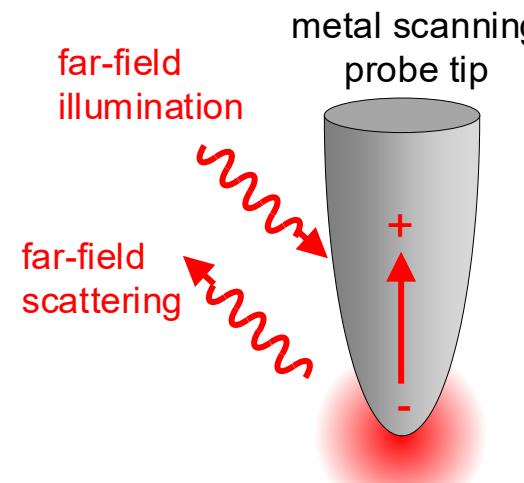
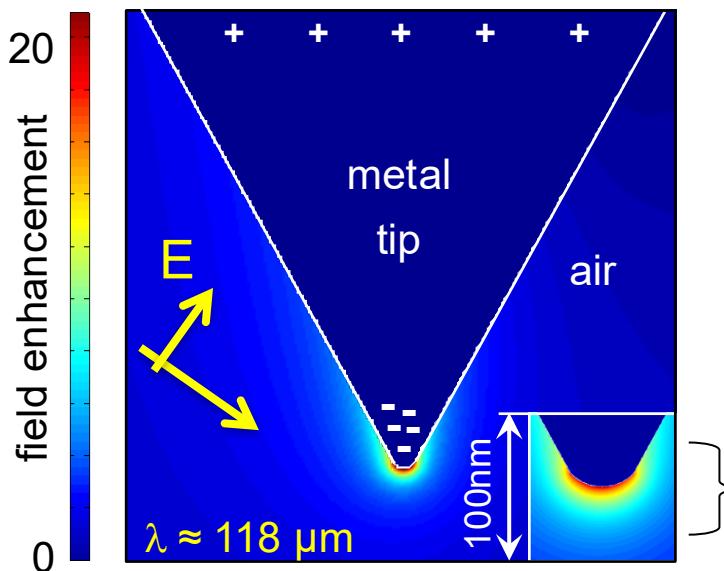




# Modern s-SNOM

(scattering-type scanning near-field optical microscopy)  
A sharp metal tip replaces the particle in Synge's idea

**Strong optical near-fields at a metal tip with apex diameter  $\ll \lambda$**   
(numerical calculation)



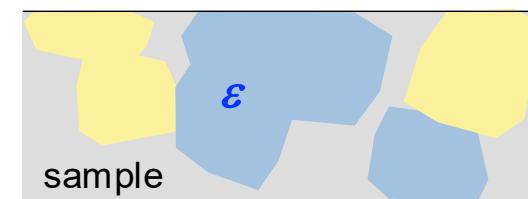
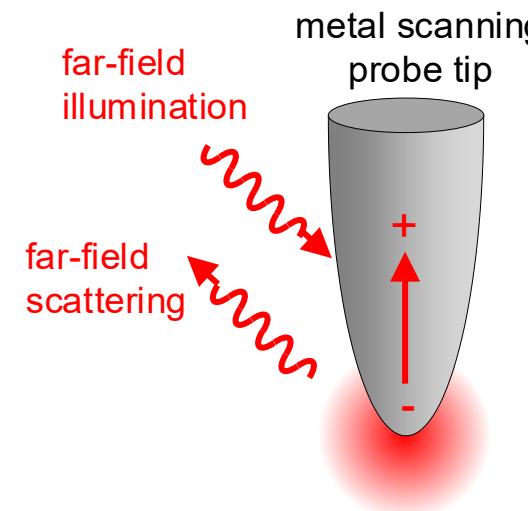
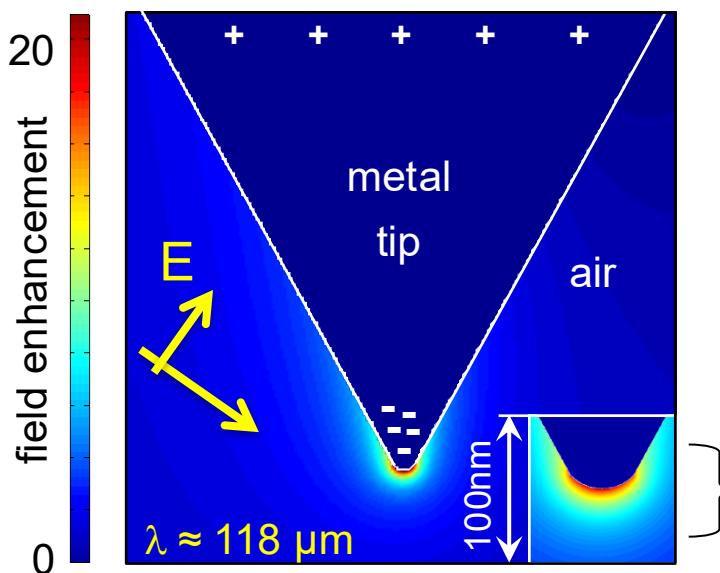
A.J. Huber, F. Keilmann, J. Wittborn, J. Aizpurua,  
R. Hillenbrand, *Nano Lett.* **8**, 3766 (2008)



# Modern s-SNOM

(scattering-type scanning near-field optical microscopy)  
A sharp metal tip replaces the particle in Synge's idea

Strong optical near-fields at a metal tip with apex diameter  $\ll \lambda$   
(numerical calculation)



Near-field optical excitation of the sample yields

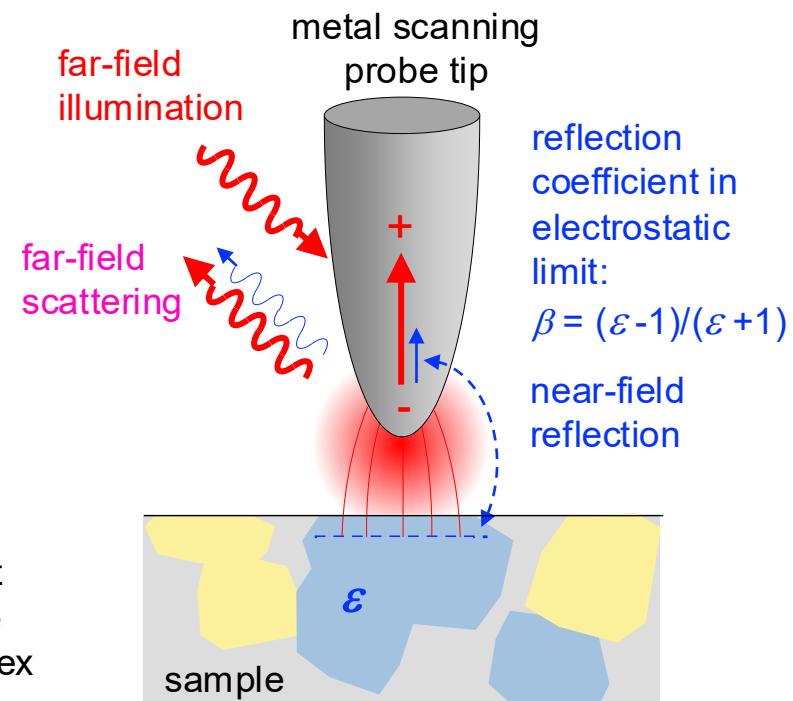
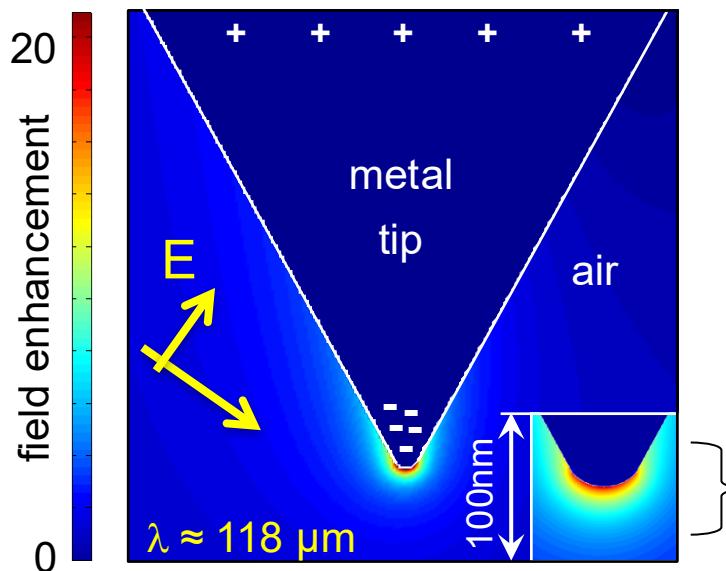
- Elastic scattering (vis, IR, THz,...)
- Inelastic scattering (e.g. Raman → TERS)  
[Novotny, Deckert, Hartschuh, Kawata, Raschke]
- SHG, SFG,...

A.J. Huber, F. Keilmann, J. Wittborn, J. Aizpurua,  
R. Hillenbrand, *Nano Lett.* **8**, 3766 (2008)

# Reflection of near field leads to addition scattering form the tip depending on sample properties



Strong optical near-fields at a metal tip with apex diameter  $\ll \lambda$   
(numerical calculation)



A.J. Huber, F. Keilmann, J. Wittborn, J. Aizpurua,  
R. Hillenbrand, *Nano Lett.* **8**, 3766 (2008)

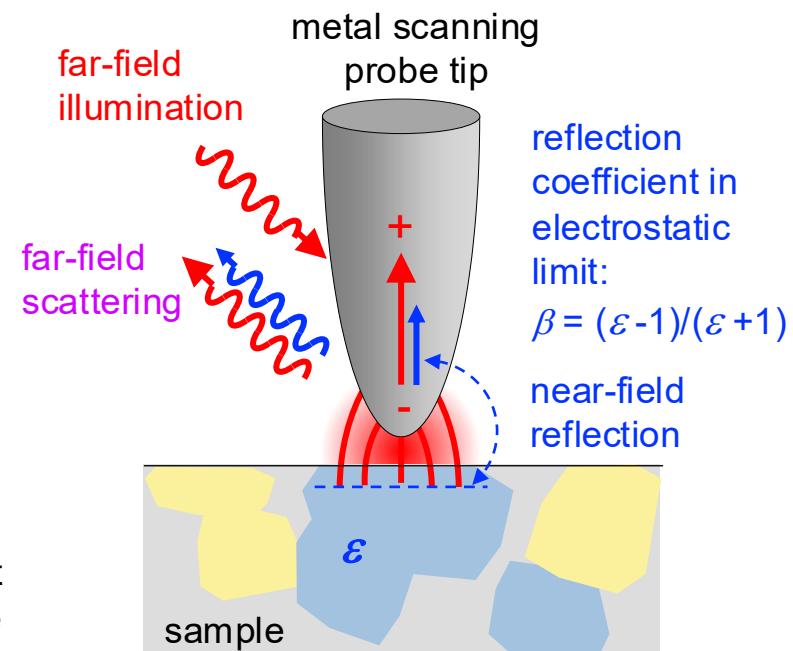
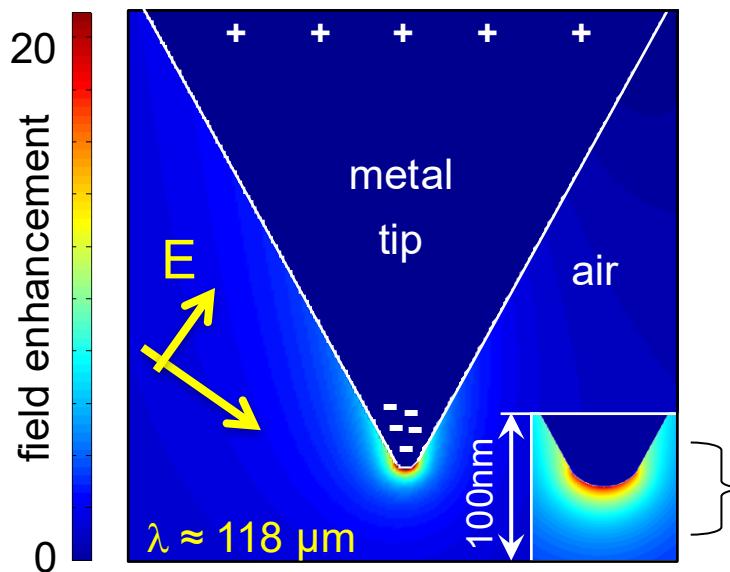
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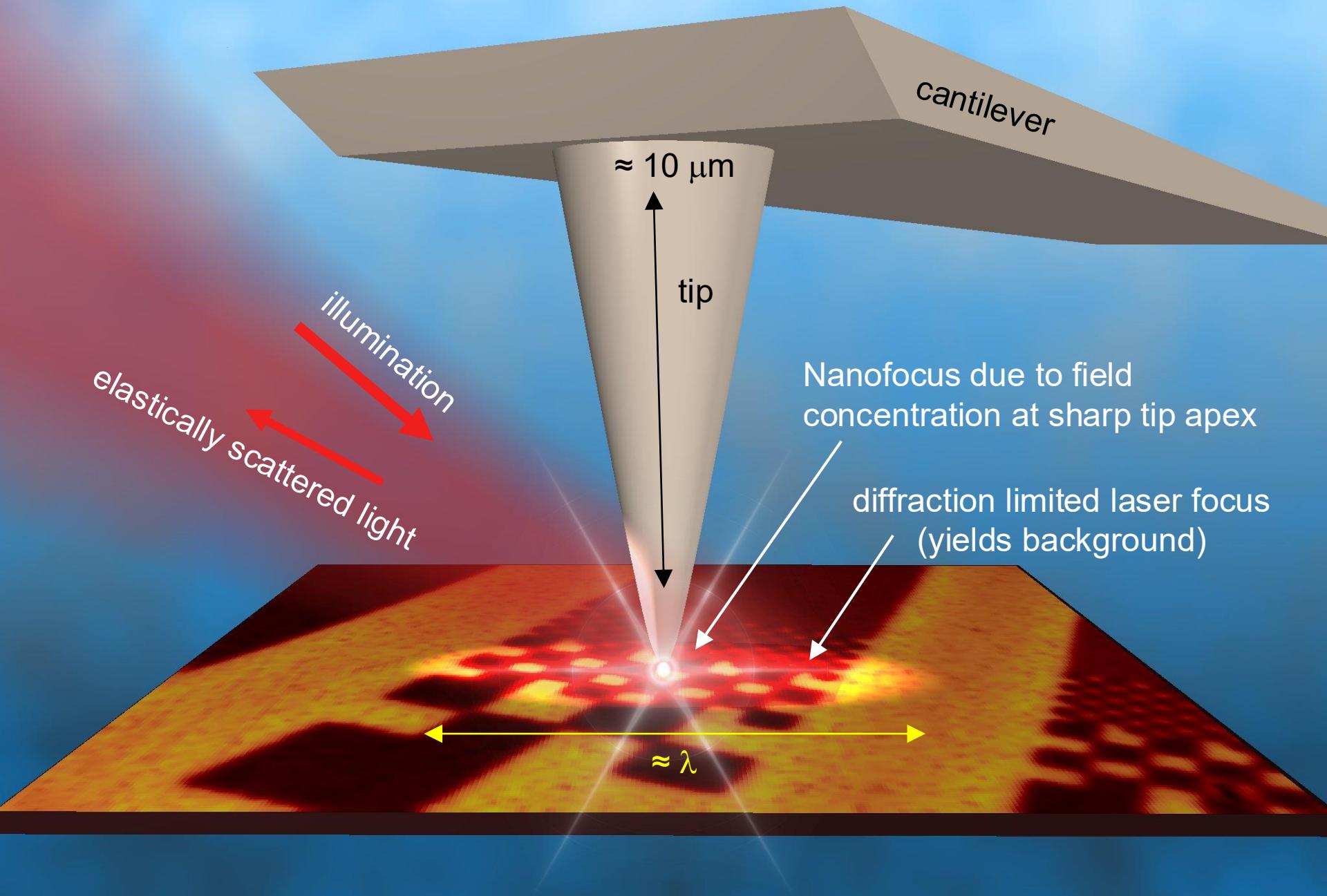


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R. Hillenbrand, *Nano Lett.* **8**, 3766 (2008)

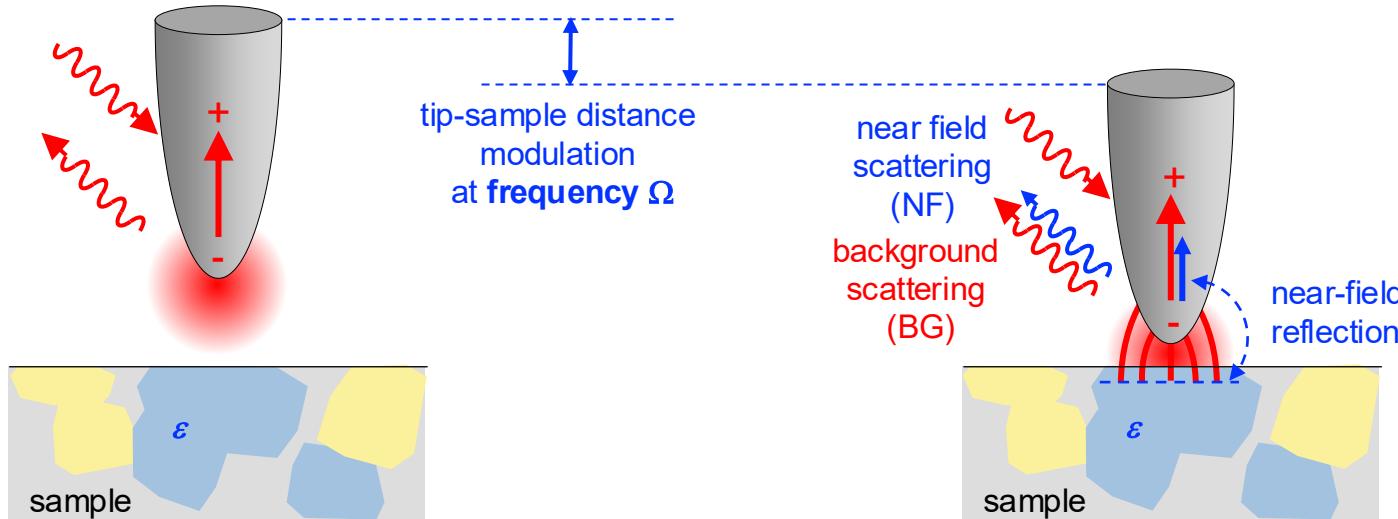
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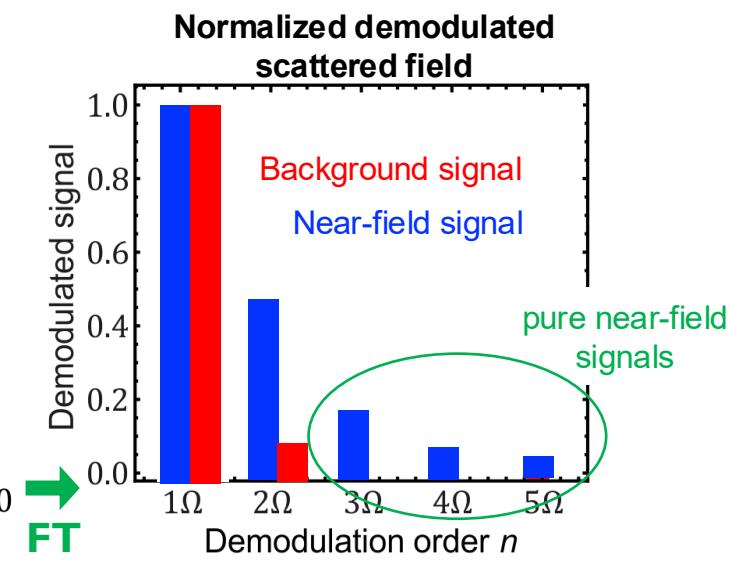
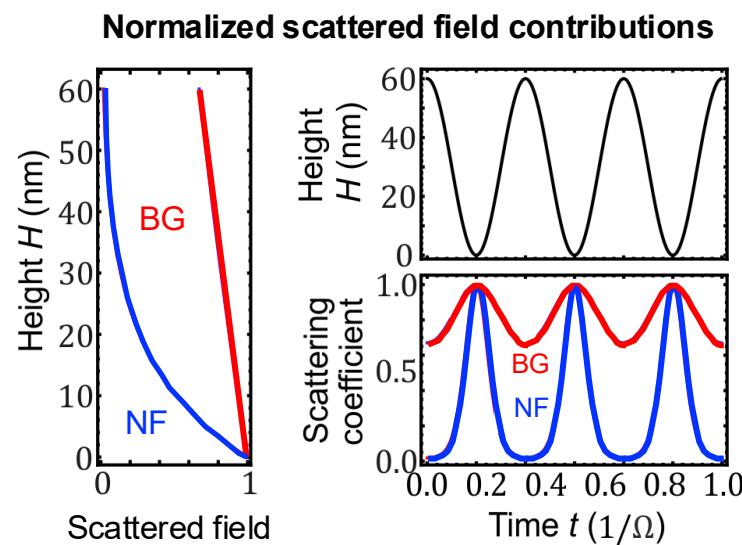
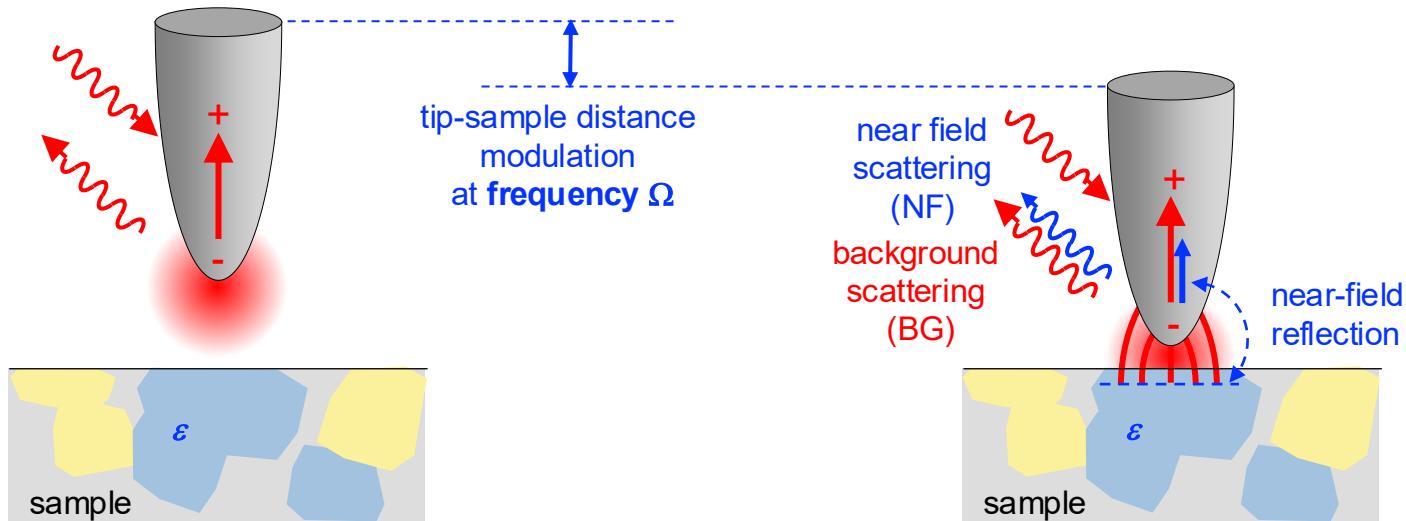
# Breaking the diffraction barrier by light scattering at a sharp tip



# Modulation of tip-sample distance yields higher near-field signal harmonics



# Modulation of tip-sample distance yields higher near-field signal harmonics

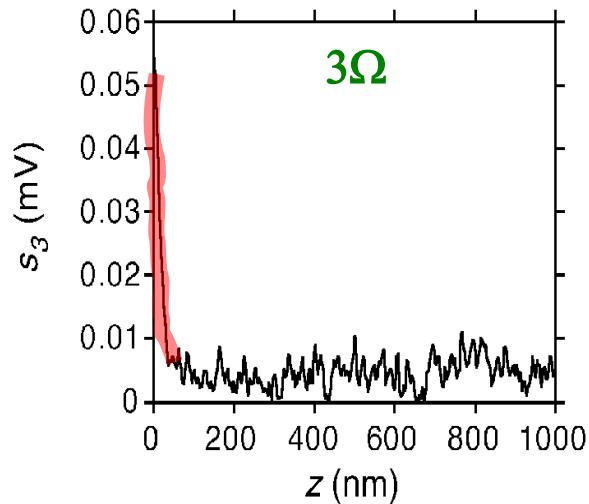
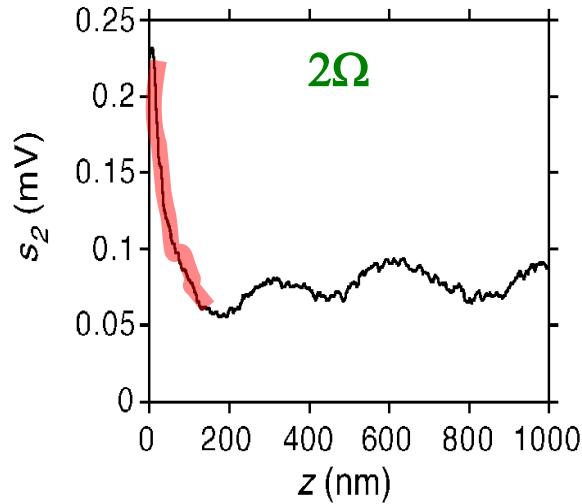
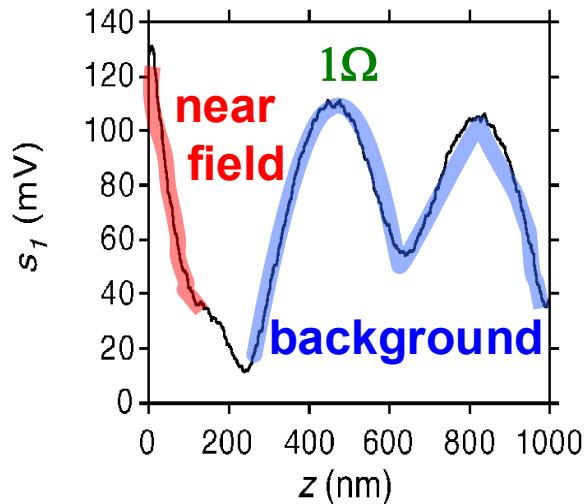


# Modulation of tip-sample distance yields higher near-field signal harmonics



$s_n$  = signal demodulated at tapping frequency  $n\Omega$

$\lambda = 633 \text{ nm}$

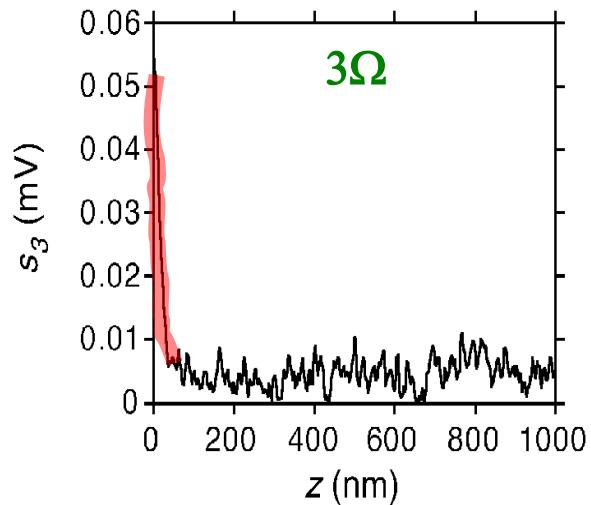
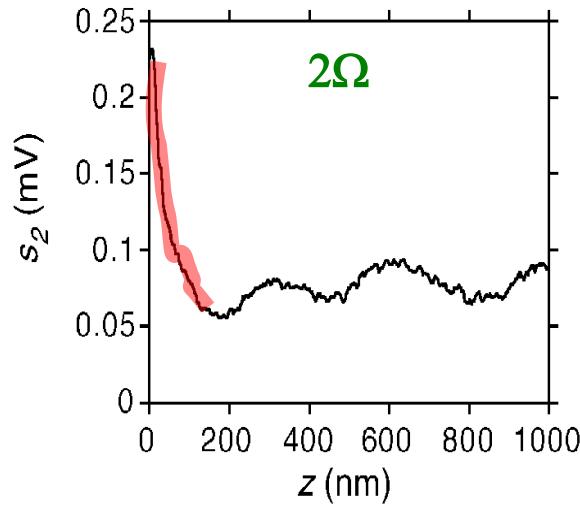
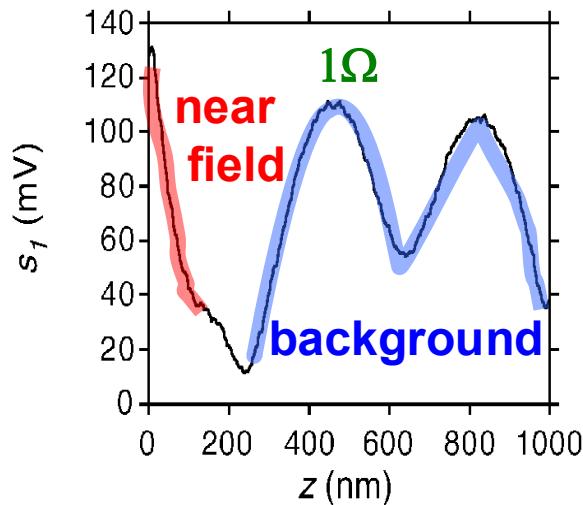


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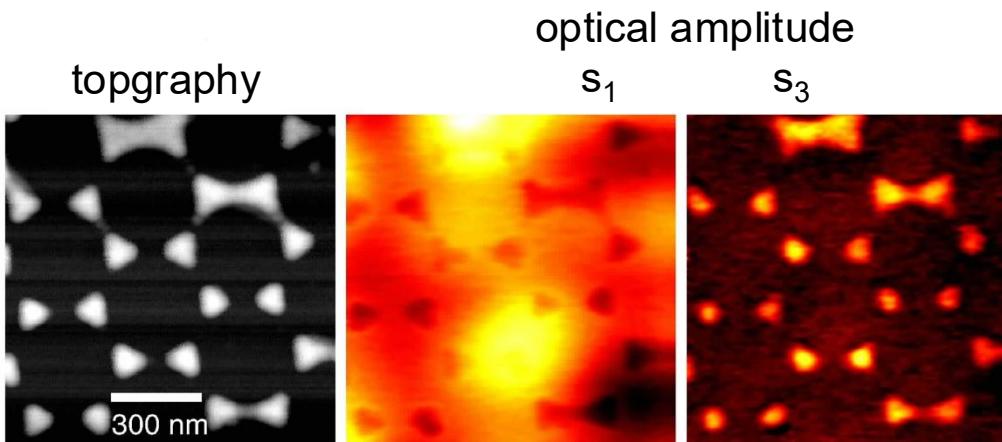


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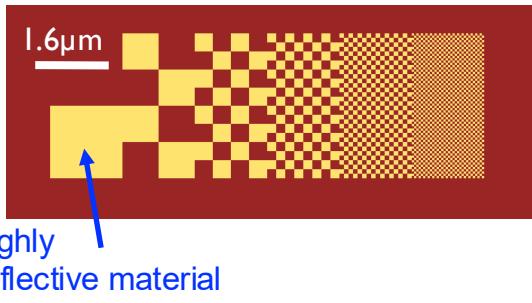
Au islands  
on Si  
surface



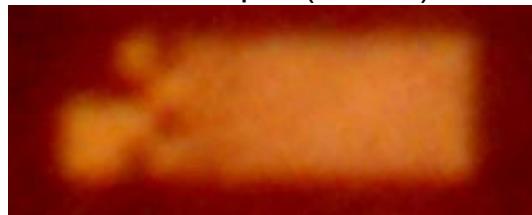
# s-SNOM beats the diffraction limit by orders of magnitude



Test Pattern



Reflection image  
 $\lambda = 0.5 \mu\text{m}$  (visible)



Reflection image  
 $\lambda = 10 \mu\text{m}$  (infrared)

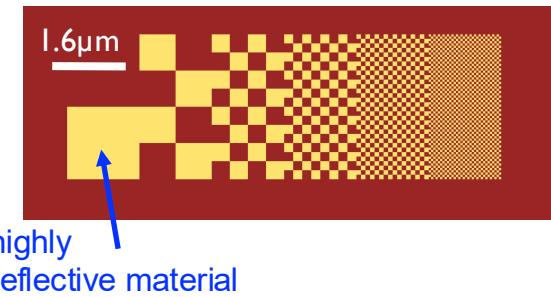


Diffraction prevents to resolve the of smallest structures

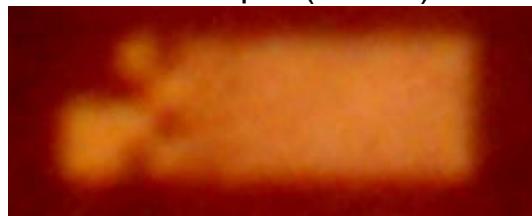
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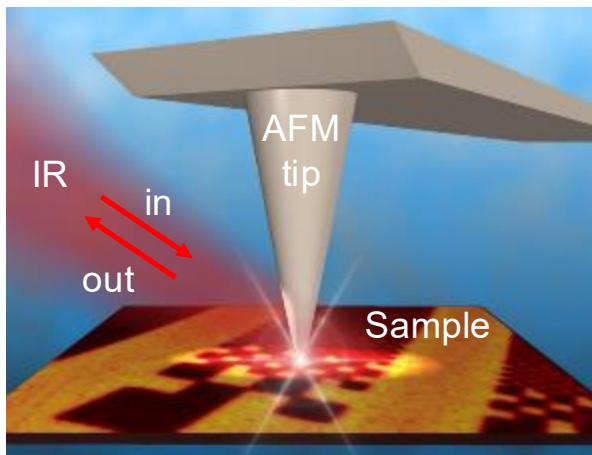
Reflection image  
 $\lambda = 10 \mu\text{m}$  (infrared)



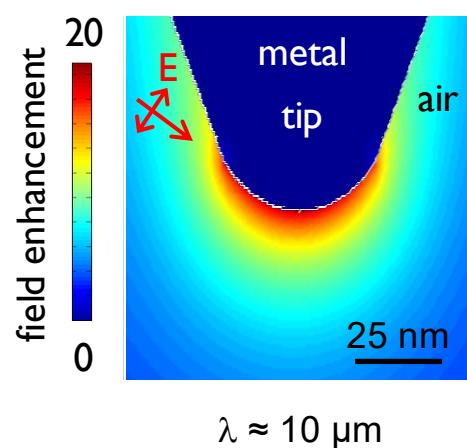
Diffraction prevents to resolve the of smallest structures

## Near-field IR microscopy (s-SNOM or nano-FTIR) overcomes diffraction limit by orders of magnitude

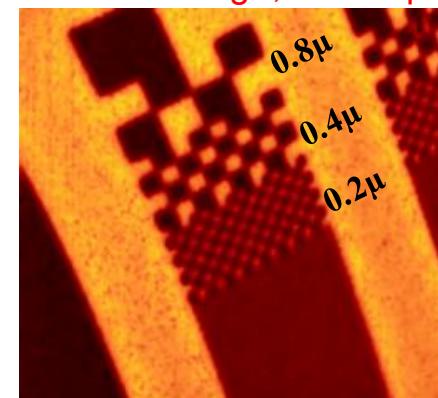
Focused laser beam illuminates AFM tip



Tip creates nano-focus

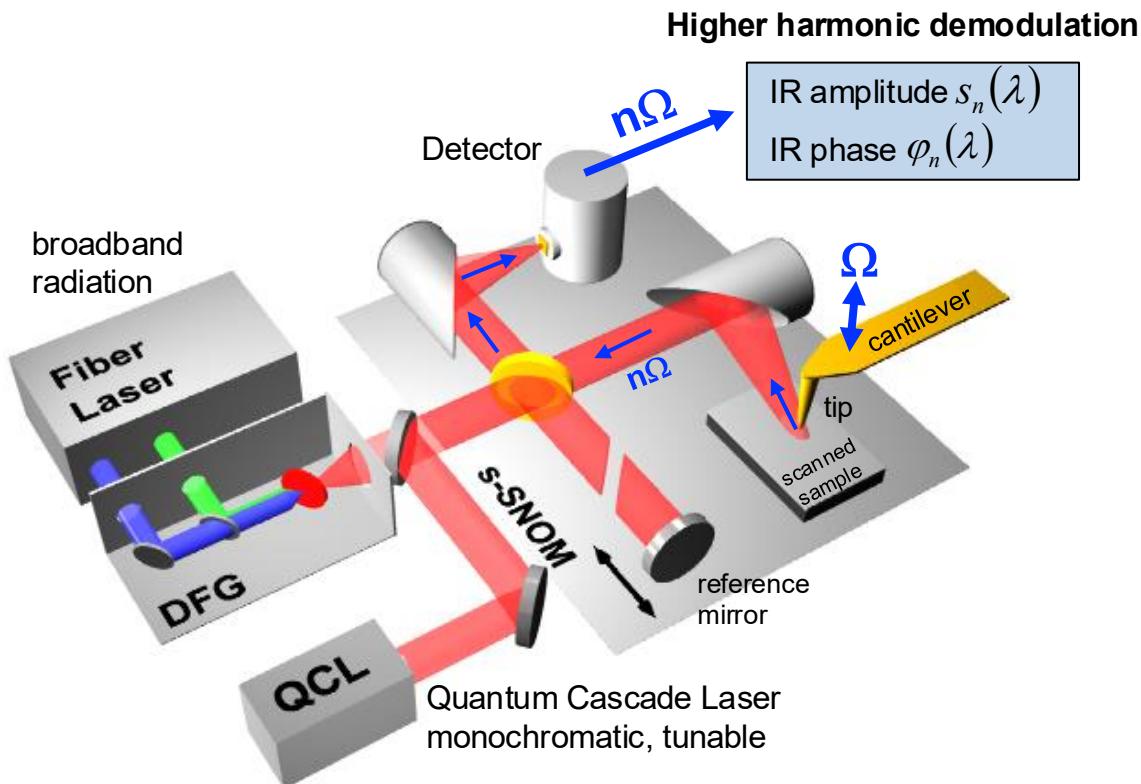


Recorded tip-scattered field yields near-field image;  $\lambda = 10 \mu\text{m}$



*Nature Materials* 3, 606 (2004)

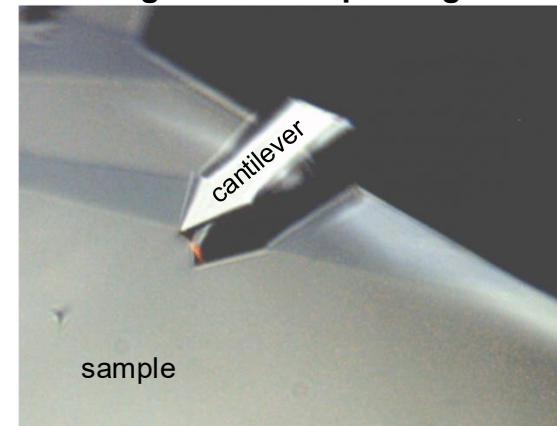
# Typical setup of interferometric s-SNOM/nano-FTIR



Electron microscope image



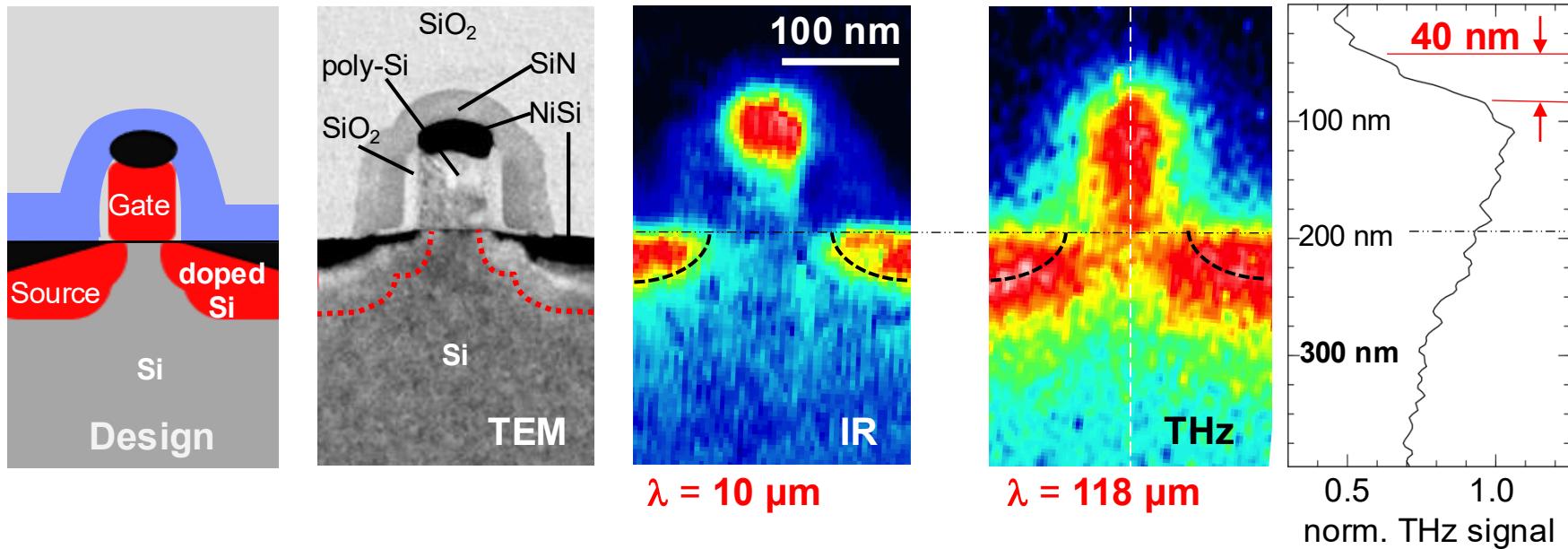
Light microscope image



- Accessible wavelength range 0.5 – 500  $\mu$ m
- Higher harmonic demodulation + interferometric detection scheme yields background-free, spectroscopic near-field signals

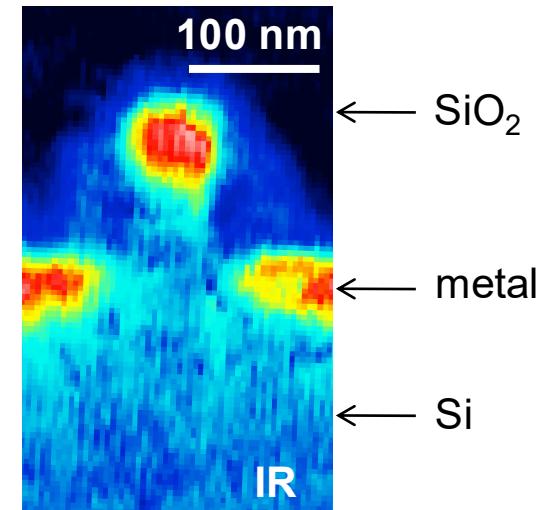
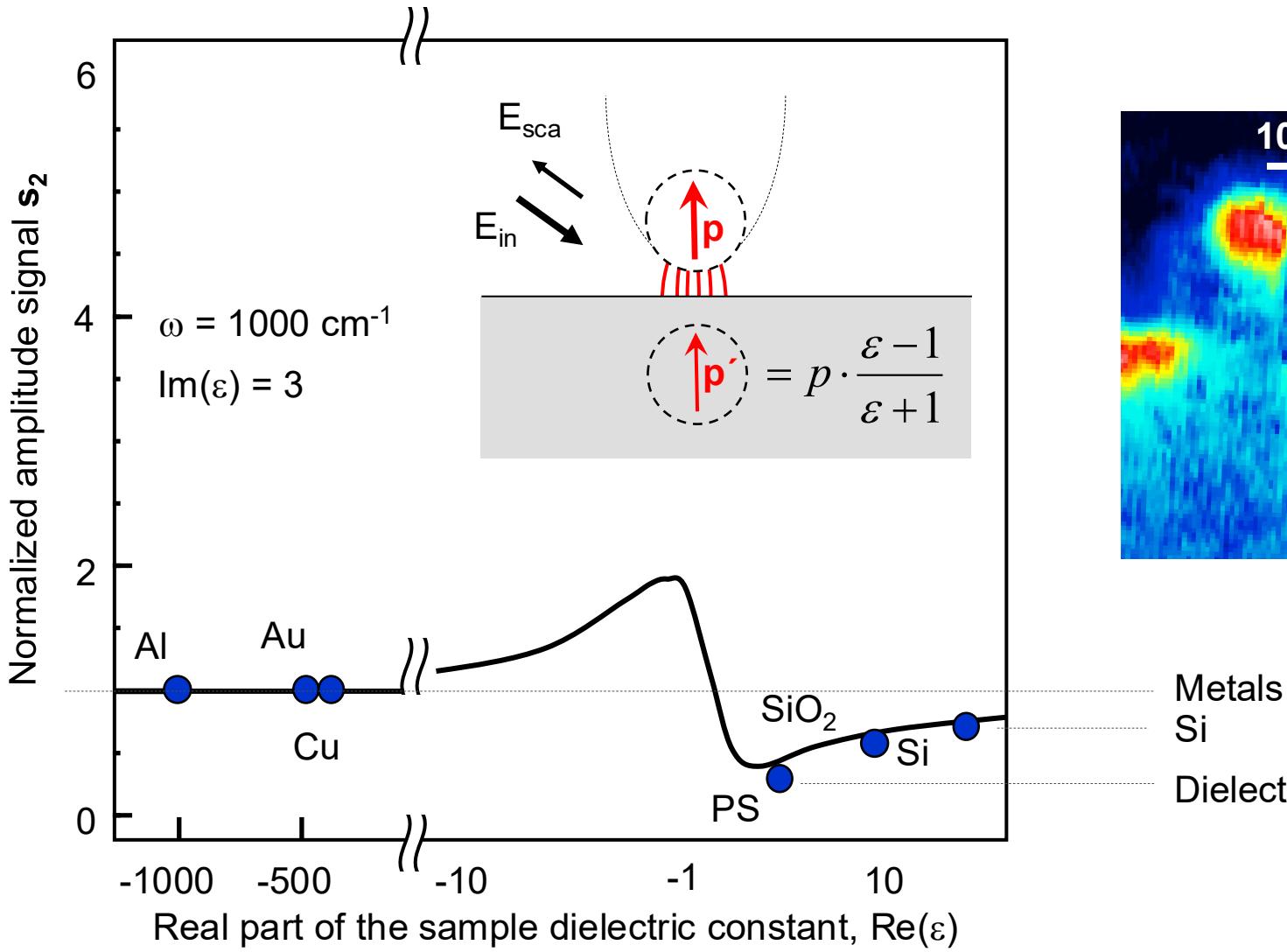
**Pseudoheterodyne detection:** N. Ocelic, A. Huber, R. Hillenbrand, *Appl. Phys. Lett.* **89**, 101124 (2006)  
**nano-FTIR spectroscopy:** F. Huth, et al. *Nano Lett.* **12**, 3973 (2012)

# IR/THz s-SNOM can map materials and free-carriers with nanoscale resolution



- ⇒ substructure of single 65 nm-transistor can be characterized with IR-THz s-SNOM
  - s-SNOM offers nanoscale spatial resolution at IR and THz frequencies
  - We already achieve **40 nm** resolution at **118 μm** ( $= \lambda/3000$ )
  - Enables quantitative and nanoscale resolved mapping of free carriers

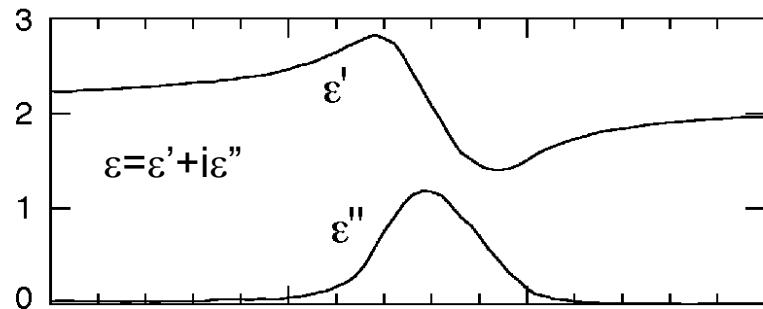
# Dipole model describes material contrast based on tip-sample near-field interaction



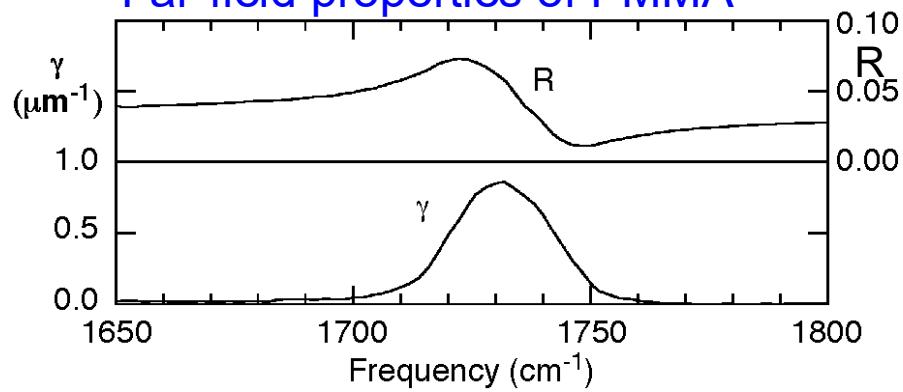
# Far-field vs. s-SNOM spectra



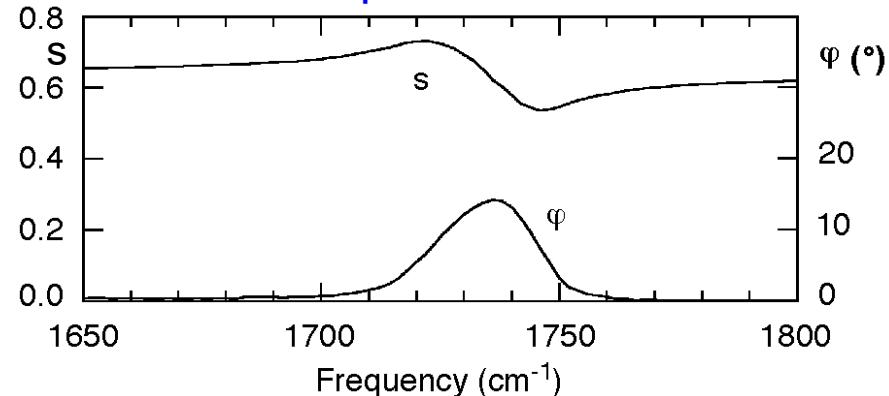
Dielectric function of PMMA



Far-field properties of PMMA



s-SNOM response of PMMA

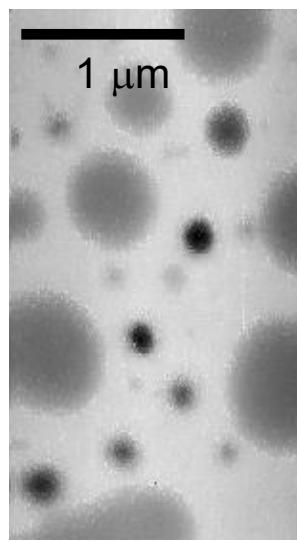
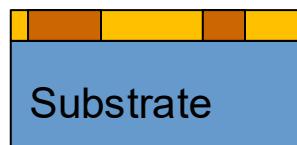


→ Near-field amplitude behaves much like far-field reflectivity  
Near-field phase behaves much like far-field absorption

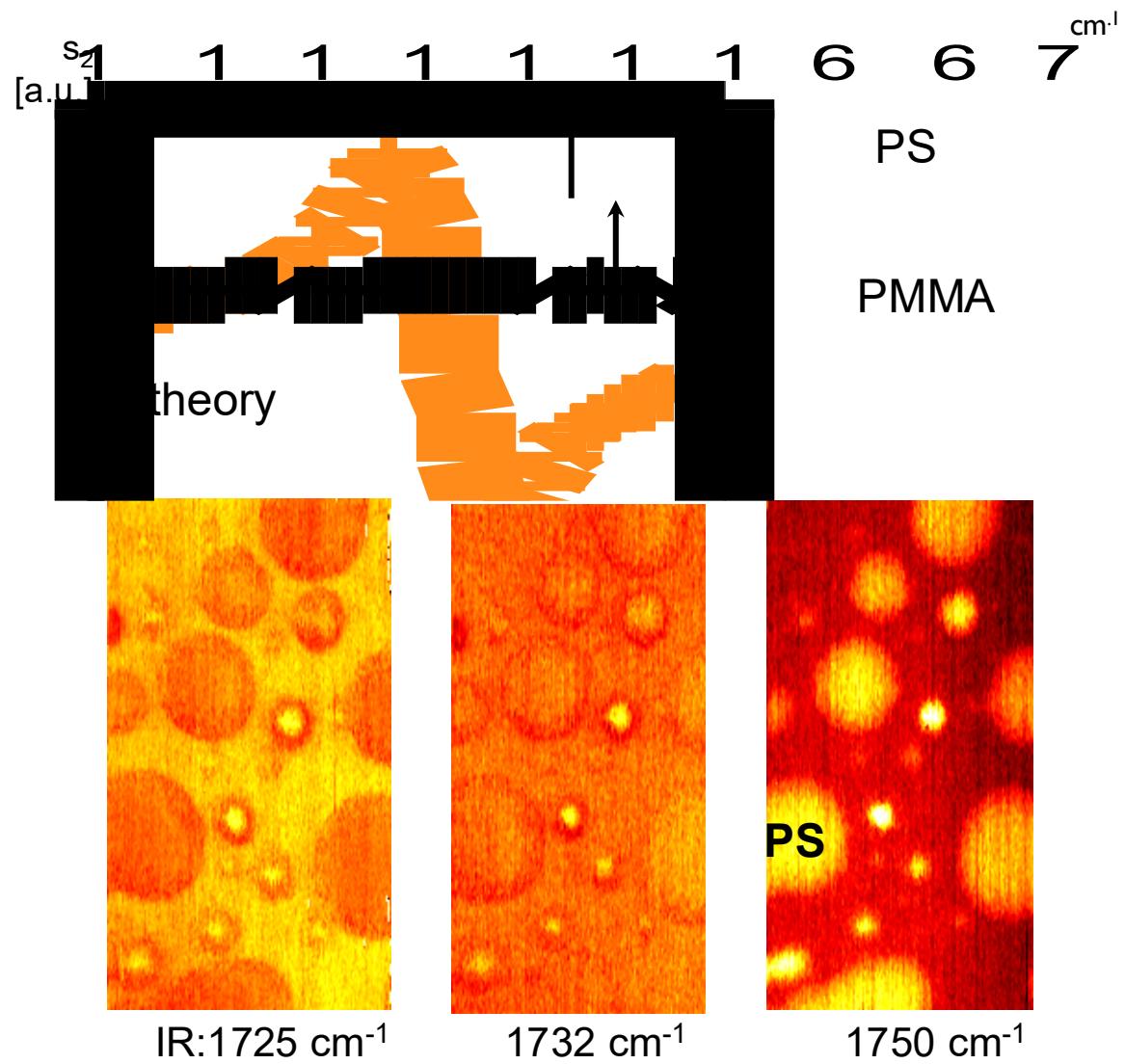
# IR s-SNOM allows for nanoscale chemical mapping of polymer blends



70 nm thick film of PS/PMMA polymer blend on Si surface

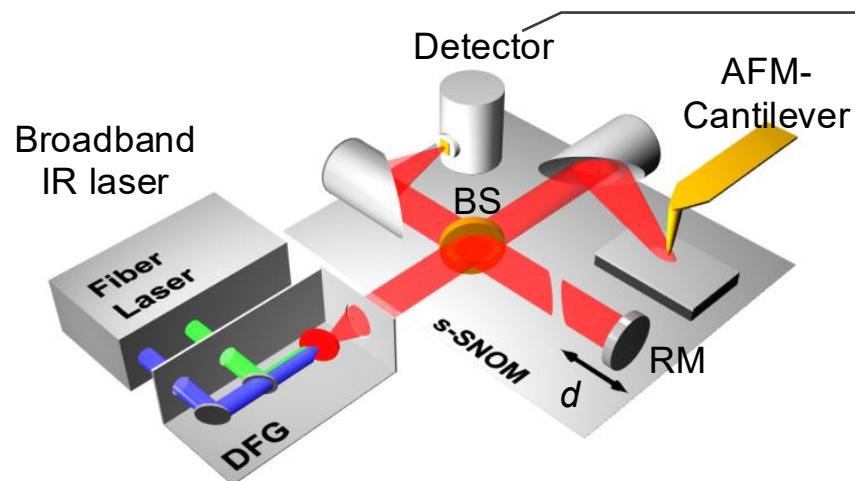


topography

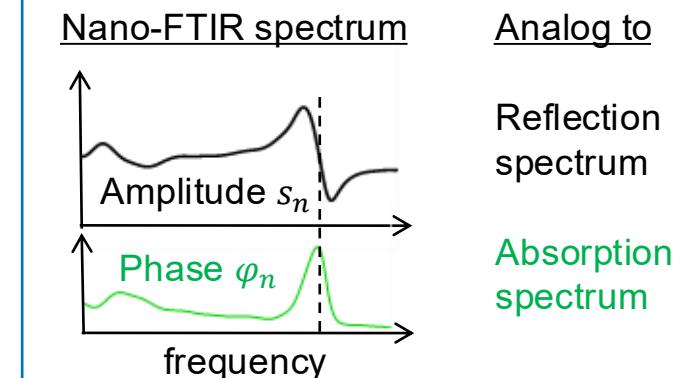
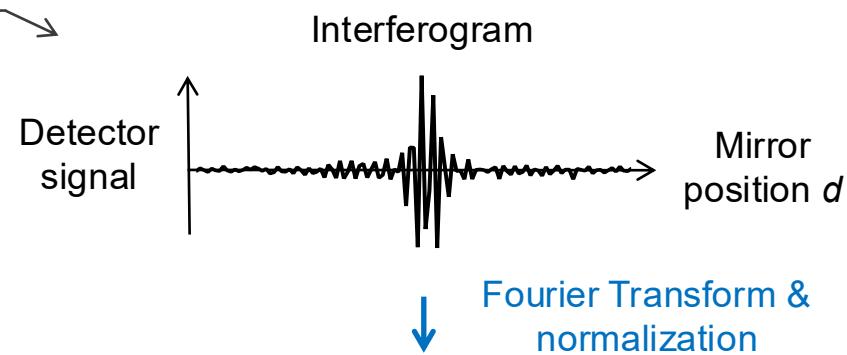
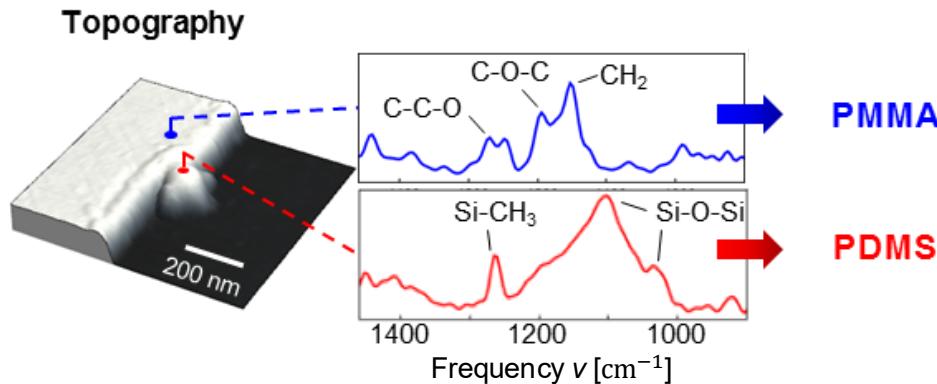


T. Taubner, R. Hillenbrand, F. Keilmann, *Appl. Phys. Lett.* **85**, 5064 (2004)

# Nanoidentification by infrared s-SNOM and Nano-FTIR



s-SNOM is based on **atomic force microscopy** and **interferometric detection of the tip-scattered light**.

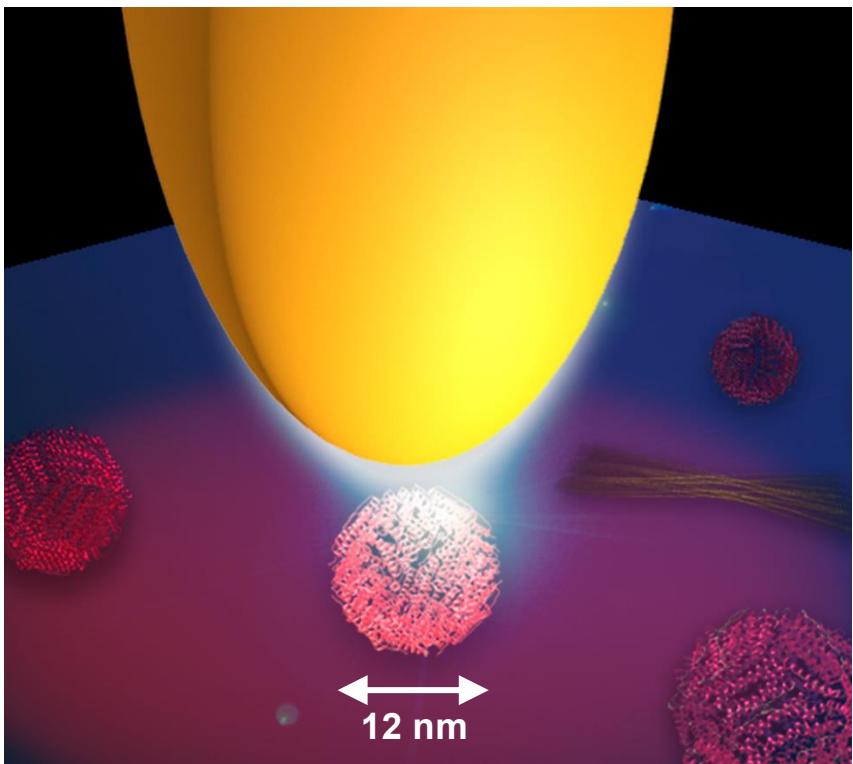


Nano-FTIR spectroscopy allows for chemical nanoidentification

# Example of s-SNOM imaging and nano-FTIR spectroscopy

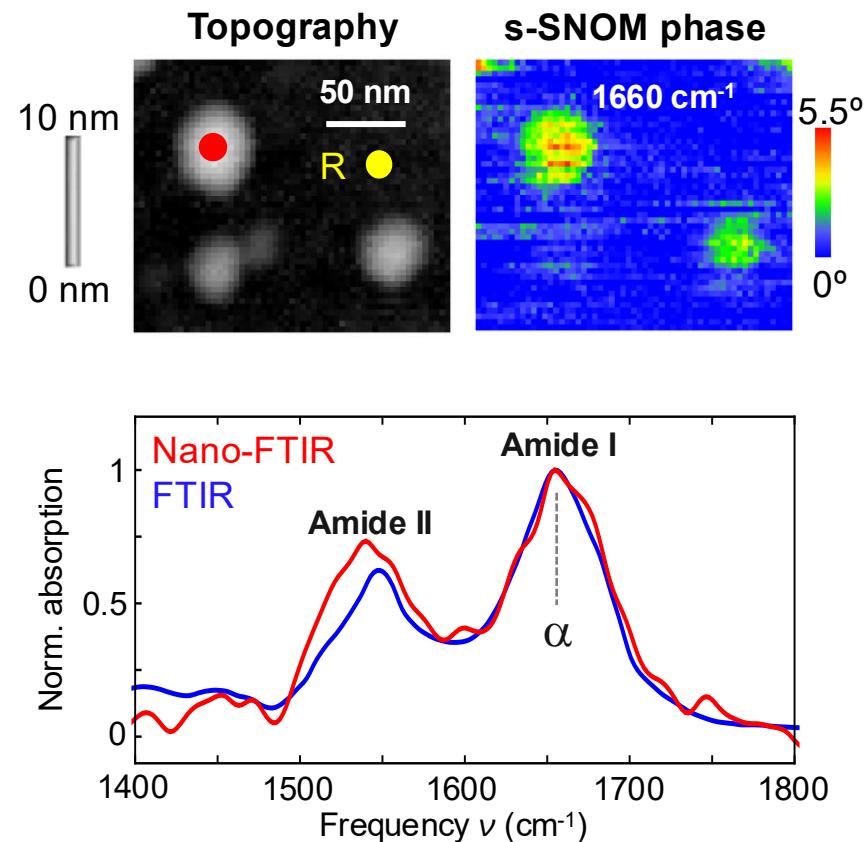


We can measure single protein complexes



## Ferritin characteristics:

- 24 proteins/subunits
- 5000 C=O bonds
- 1 attogram mass

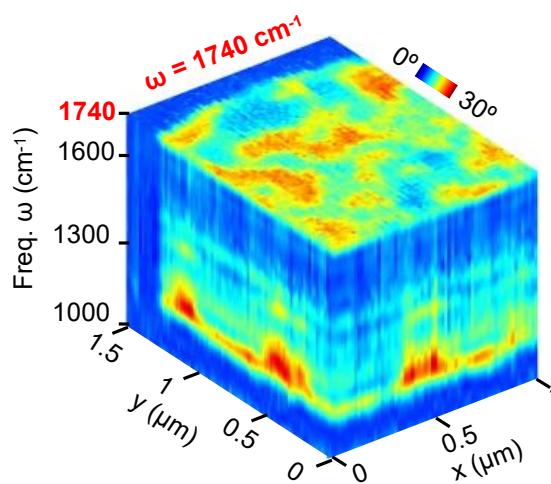


**However: Signal-to-noise-ratio goes down**  
(23 min / spectrum, limited by signal-to-noise level)

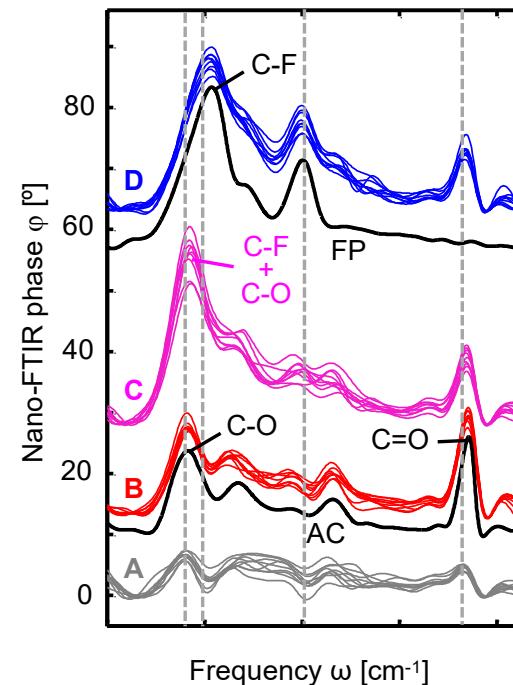
# Hyperspectral imaging and multivariate analysis yields maps of chemical composition and interaction



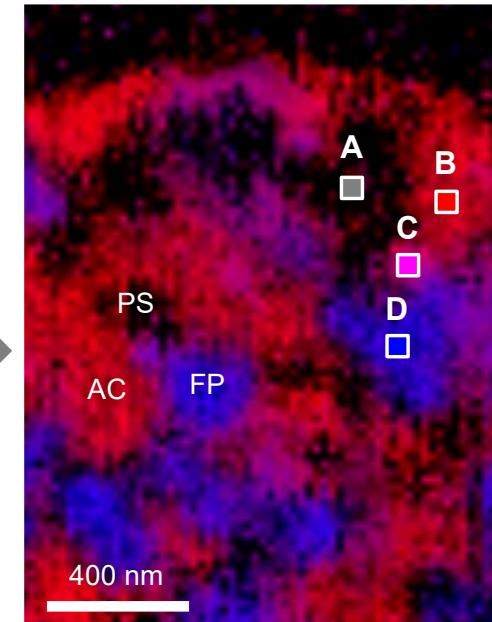
Hyperspectral data cube of three-component polymer blend



Analysis



Compositional map



Purple spectra cannot be composed of the components' spectra

fluorine copolymer (FP)  
acrylic copolymer (AC)  
polystyrene (PS)

Areas of chemical interaction



# Nano-FTIR application examples

Nano-FTIR is ready for applications ...

... and many more to come!

... in organic electronics



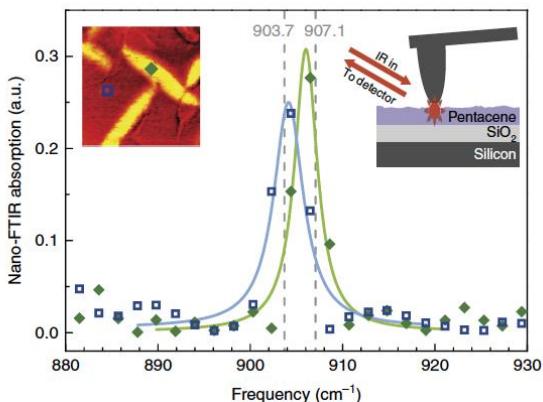
ARTICLE

Received 28 Feb 2014 | Accepted 13 May 2014 | Published 11 Jun 2014

DOI: 10.1038/ncomm5101 OPEN

Sub-micron phase coexistence in small-molecule organic thin films revealed by infrared nano-imaging

Christian Westermeier<sup>1,2</sup>, Adrian Cernescu<sup>1,3</sup>, Sergiu Amarie<sup>3</sup>, Clemens Liewald<sup>1</sup>, Fritz Keilmann<sup>1</sup> & Bert Nickel<sup>1,2</sup>



... in bio-chemistry



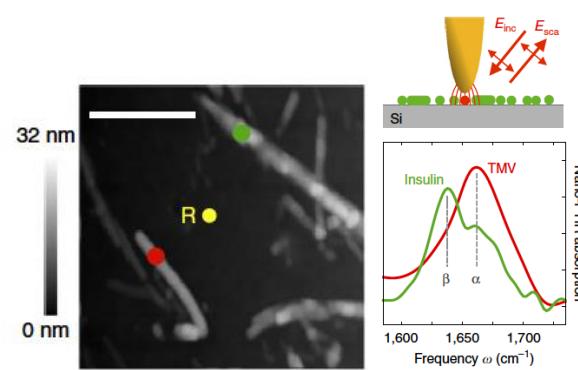
ARTICLE

Received 12 Jul 2013 | Accepted 7 Nov 2013 | Published 4 Dec 2013

DOI: 10.1038/ncomm3890 OPEN

Structural analysis and mapping of individual protein complexes by infrared nanospectroscopy

Iban Amenabar<sup>1</sup>, Simon Poly<sup>1</sup>, Wiwat Nuansing<sup>1</sup>, Elmar H. Hubrich<sup>2</sup>, Alexander A. Goyadinov<sup>1</sup>, Florian Huth<sup>1,3</sup>, Roman Krutokhvostov<sup>1</sup>, Lanbing Zhang<sup>1</sup>, Mato Knez<sup>2,4</sup>, Joachim Heberle<sup>2</sup>, Alexander M. Bittner<sup>1,4</sup> & Rainer Hillenbrand<sup>1,4</sup>



... in astro-geo-physics



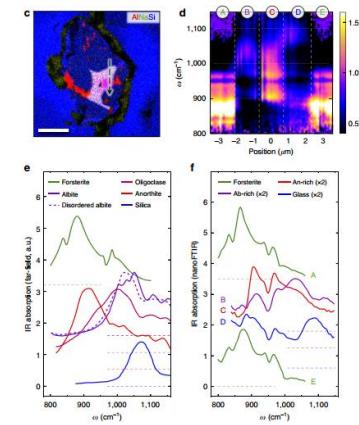
ARTICLE

Received 3 Apr 2014 | Accepted 2 Oct 2014 | Published 9 Dec 2014

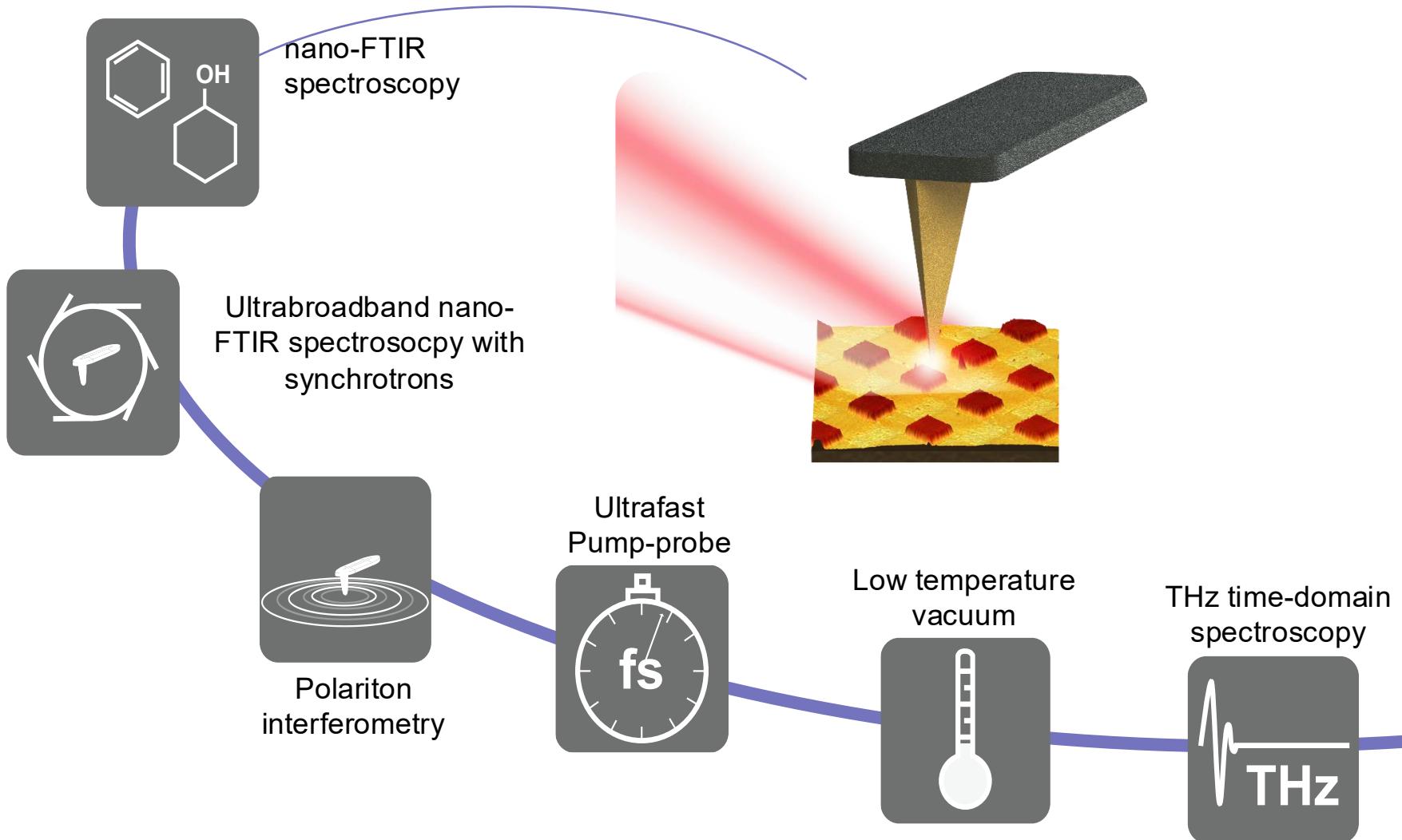
DOI: 10.1038/ncomm5445

Nanoscale infrared spectroscopy as a non-destructive probe of extraterrestrial samples

Gerardo Dominguez<sup>1,2,\*</sup>, A.S. McLeod<sup>3,\*</sup>, Zack Gainsforth<sup>4</sup>, P. Kelly<sup>3</sup>, Hans A. Bechtel<sup>5</sup>, Fritz Keilmann<sup>6</sup>, Andrew Westphal<sup>4</sup>, Mark Thiemens<sup>2</sup> & D.N. Basov<sup>3</sup>



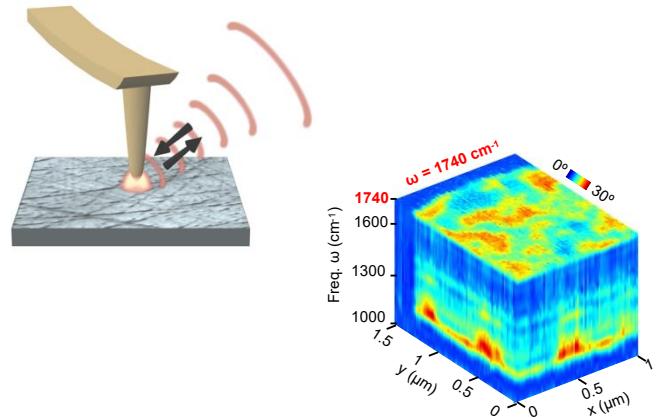
# Emerging trends





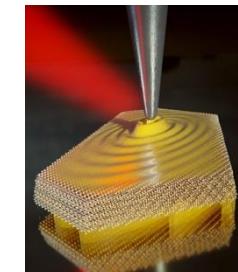
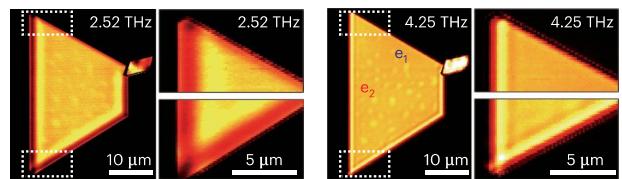
# Outline

s-SNOM and nano-FTIR techniques

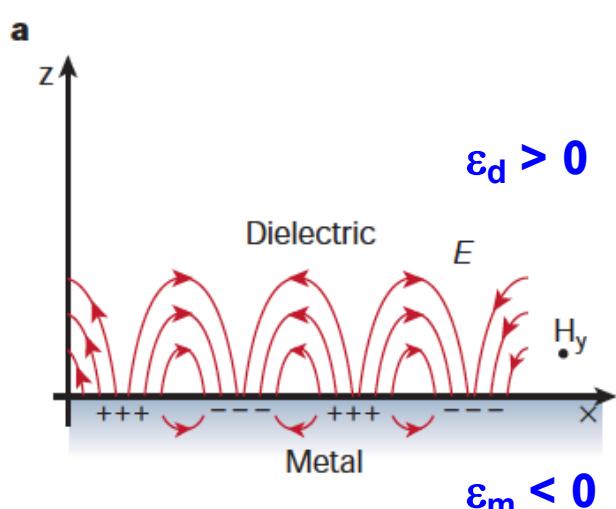


illustrated with materials characterization examples

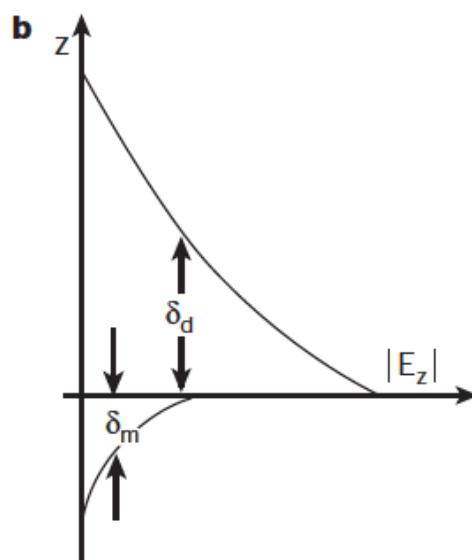
Imaging anisotropic plasmon polaritons in AgTe  
by Thz s-SNOM



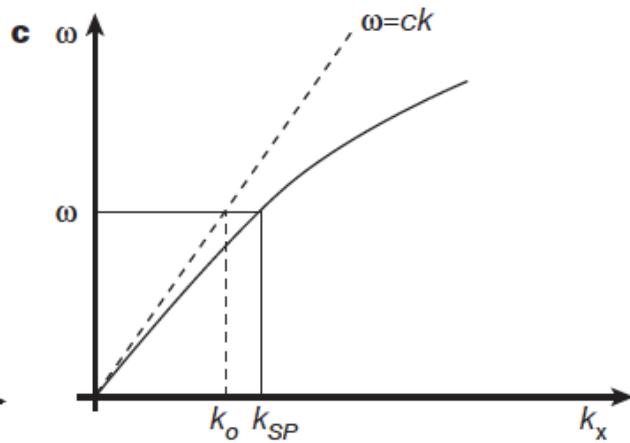
# Propagating surface plasmon polaritons (SPPs) at the metal/dielectric interface



TM surface wave of combined electromagnetic and surface charge character



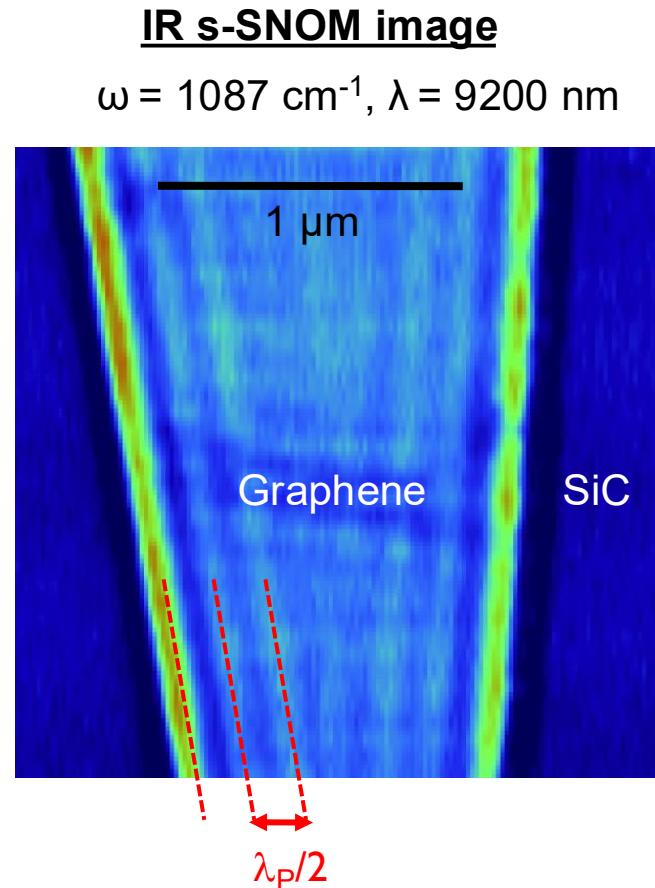
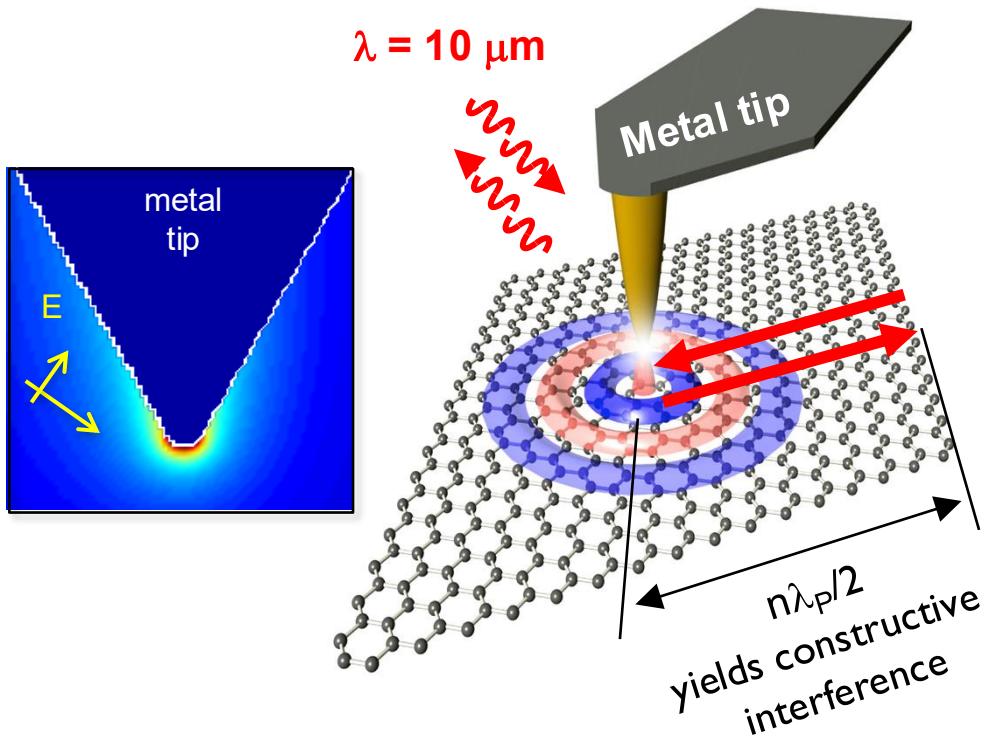
Field perpendicular to surface decays exponentially (evanescent field)



Dispersion curve shows that SPP has momentum greater than free space photon of the same frequency

Barnes, Dereux, Ebbesen, Nature 424, 824 (2003)

# Tip-enhanced near-field mapping of mid-IR plasmons in graphene (near-field plasmon interferometry)



The plasmon wavelength on graphene is dramatically shorter than the free-space wavelength.

$$\lambda_P \approx 230 \text{ nm} = \lambda/40$$

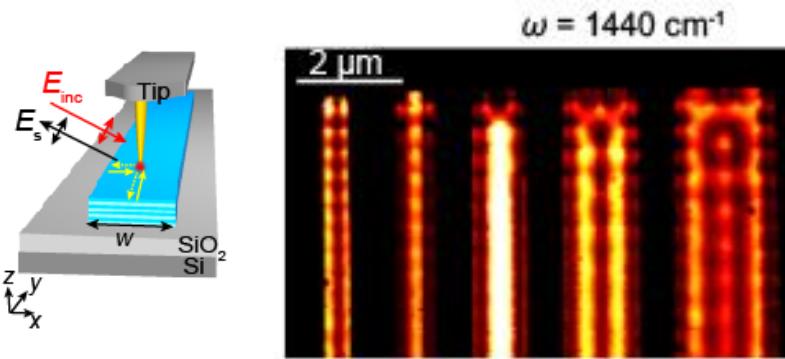
Chen et al., *Nature* **487**, 77 (2012)  
Fei et al., *Nature* **487**, 82 (2012)

# PPs are an interesting platform for infrared nanophotonics

## Some examples from our studies

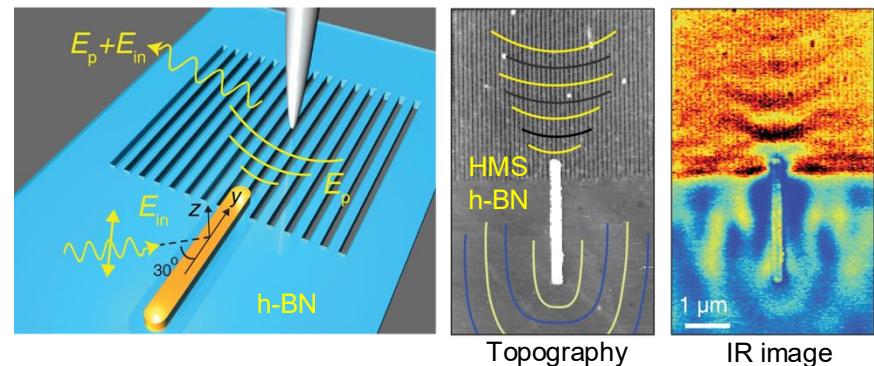


### Nanoscale guiding of mid-infrared light



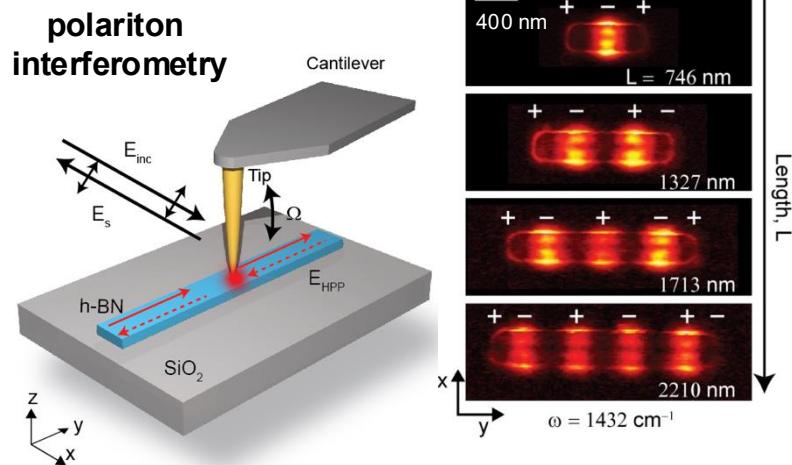
I. Dolado, et al. *Adv. Mater.* 1906530 (2020)

### Anomalous wavefronts



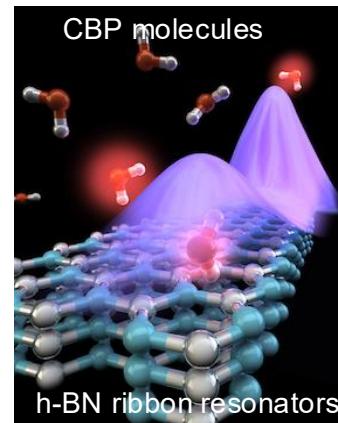
P. Li, I. Dolado, et al., *Science* 359, 892 (2018)

### PP resonators



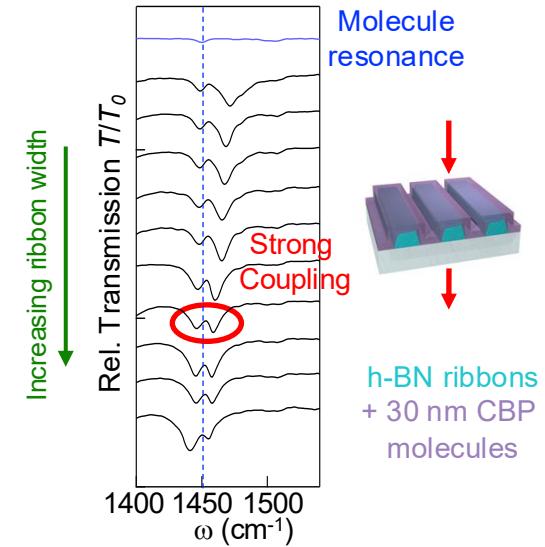
F.J. Alfaro-Mozaz et al., *Nat. Comm.* 8, 15624 (2017)

### for SEIRA



M. Autore, et al.

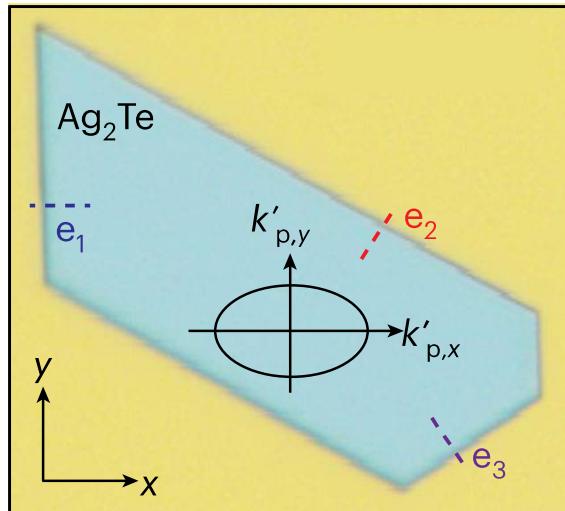
*Light Sci. Appl.* 7, 17172 (2018); *Adv. Optical Mater.* 9, 2001958 (2021)





# Ag<sub>2</sub>Te : a biaxial narrow bandgap semiconductor

Ag<sub>2</sub>Te



Optical microscope image

THz plasmon

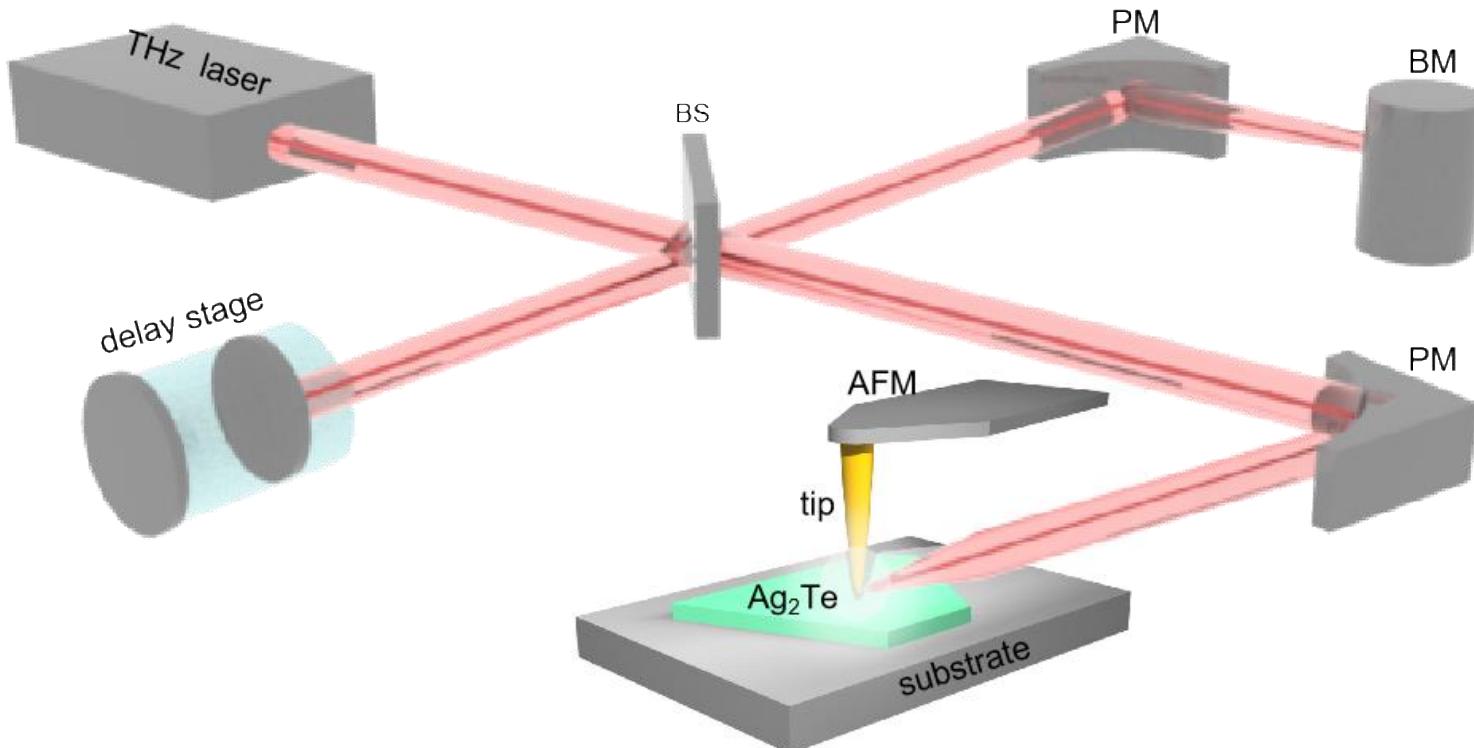
Single crystal platets grown by chemical vapour deposition

Narrow-bandgap (0.06eV)  
electron concentrations  $10^{18}$  cm<sup>-3</sup> at T<sub>room</sub>

In-plane anisotropy:  $\varepsilon_x \neq \varepsilon_y$



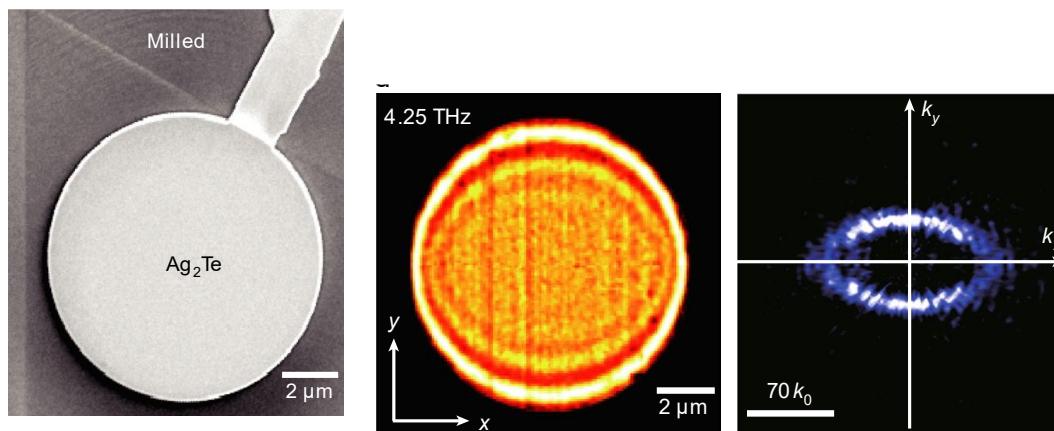
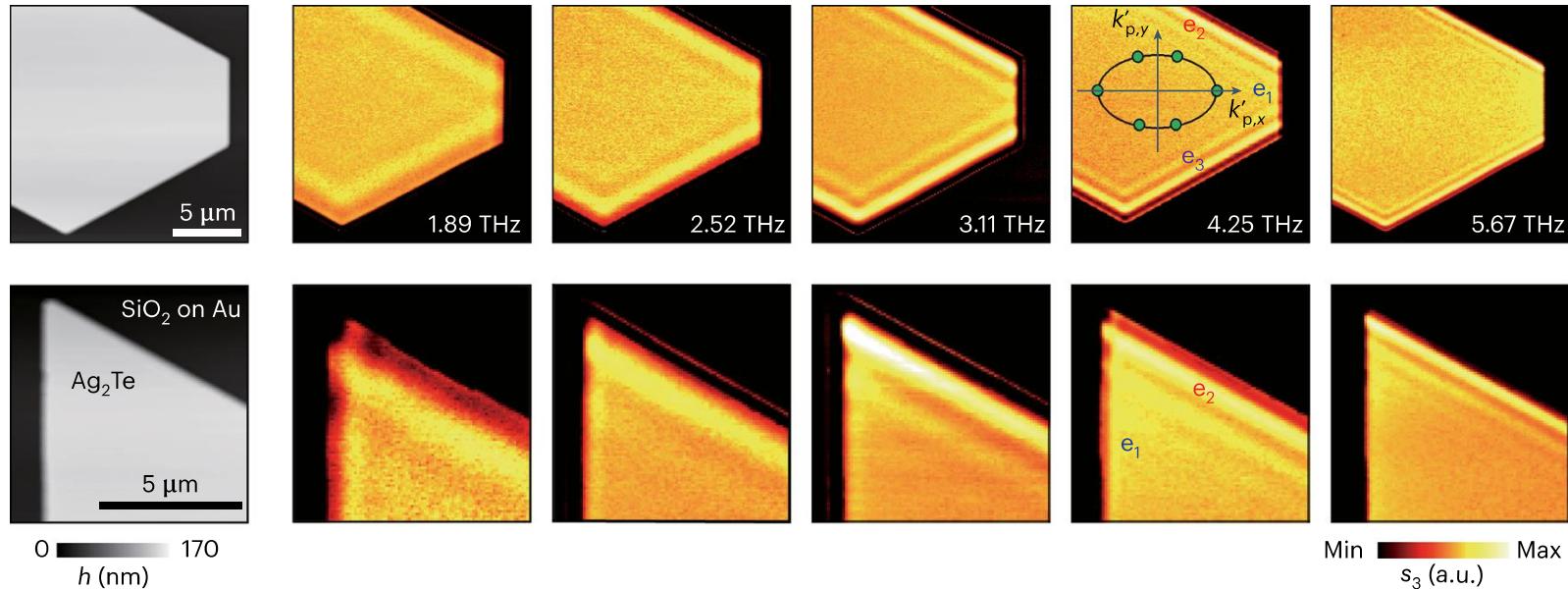
# THz plasmon polaritons setup





# THz plasmon polaritons in a $\text{Ag}_2\text{Te}$ slab

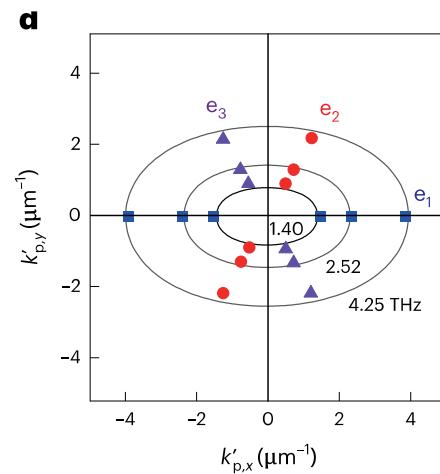
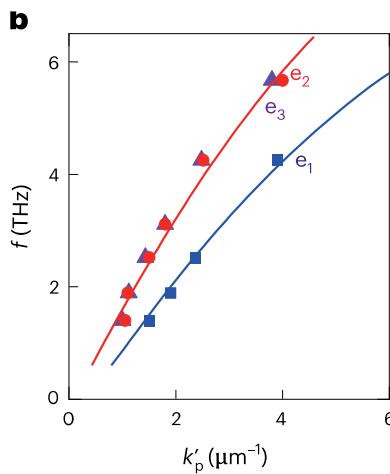
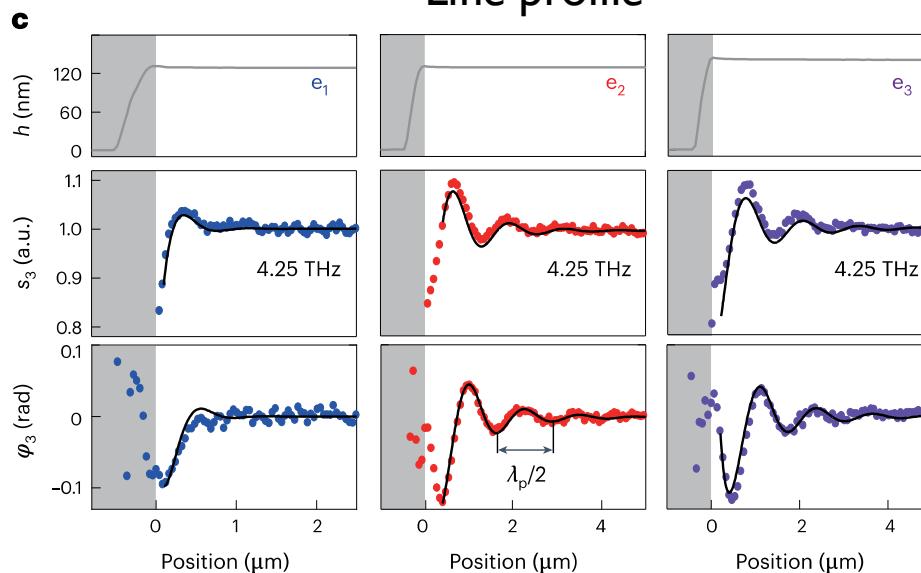
a





# THz plasmon polaritons in a $\text{Ag}_2\text{Te}$ slab

Line profile



$$\varepsilon_{xx}(\omega) = \varepsilon_{\text{IR},x} - \frac{\omega_{p,x}^2}{\omega^2 + i\gamma_x\omega}$$

$$\varepsilon_{yy}(\omega) = \varepsilon_{\text{IR},y} - \frac{\omega_{p,y}^2}{\omega^2 + i\gamma_y\omega},$$

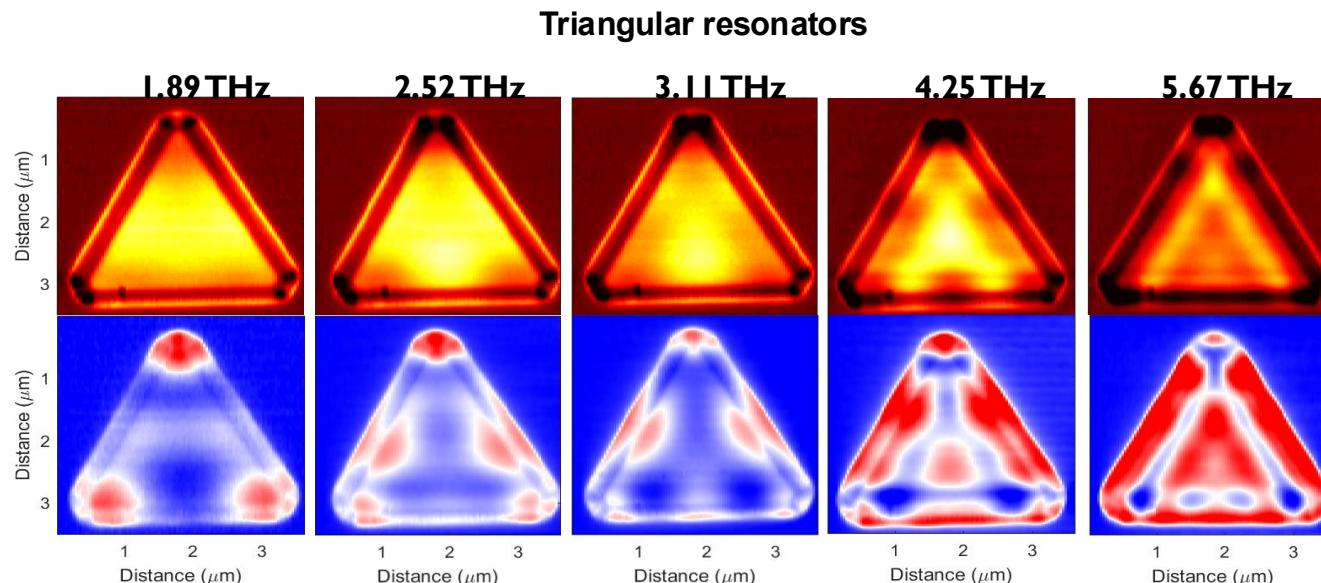
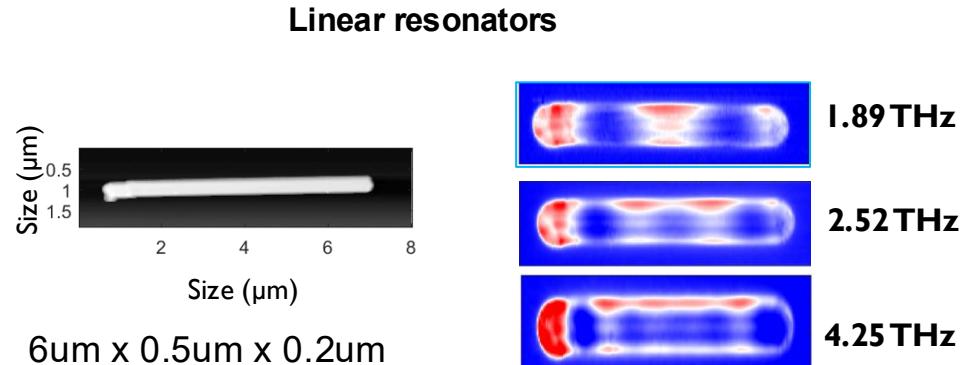
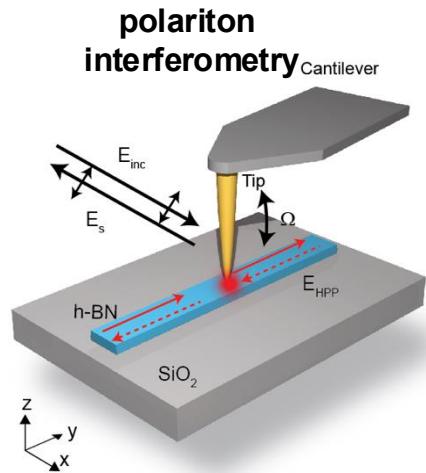
$$\omega_{p,i} = 2\pi f_{p,i} = \sqrt{\frac{ne^2}{m_{\text{eff},i}\varepsilon_0}}$$

# PPs are an interesting platform for infrared nanophotonics

## What next?



### $\text{Ag}_2\text{Te}$ plasmon polariton resonators



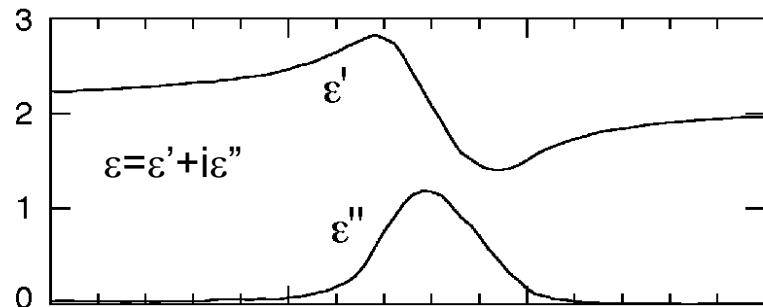


Thank you for the attention

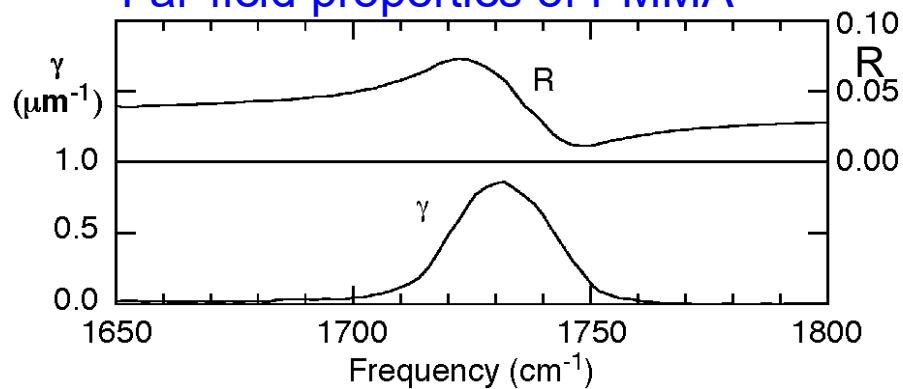


# Molecular vibrations: Far-field spectra

Dielectric function of PMMA



Far-field properties of PMMA



complex refractive index

$$n + i\kappa = \sqrt{\epsilon' + i\epsilon''}$$

far-field reflectivity

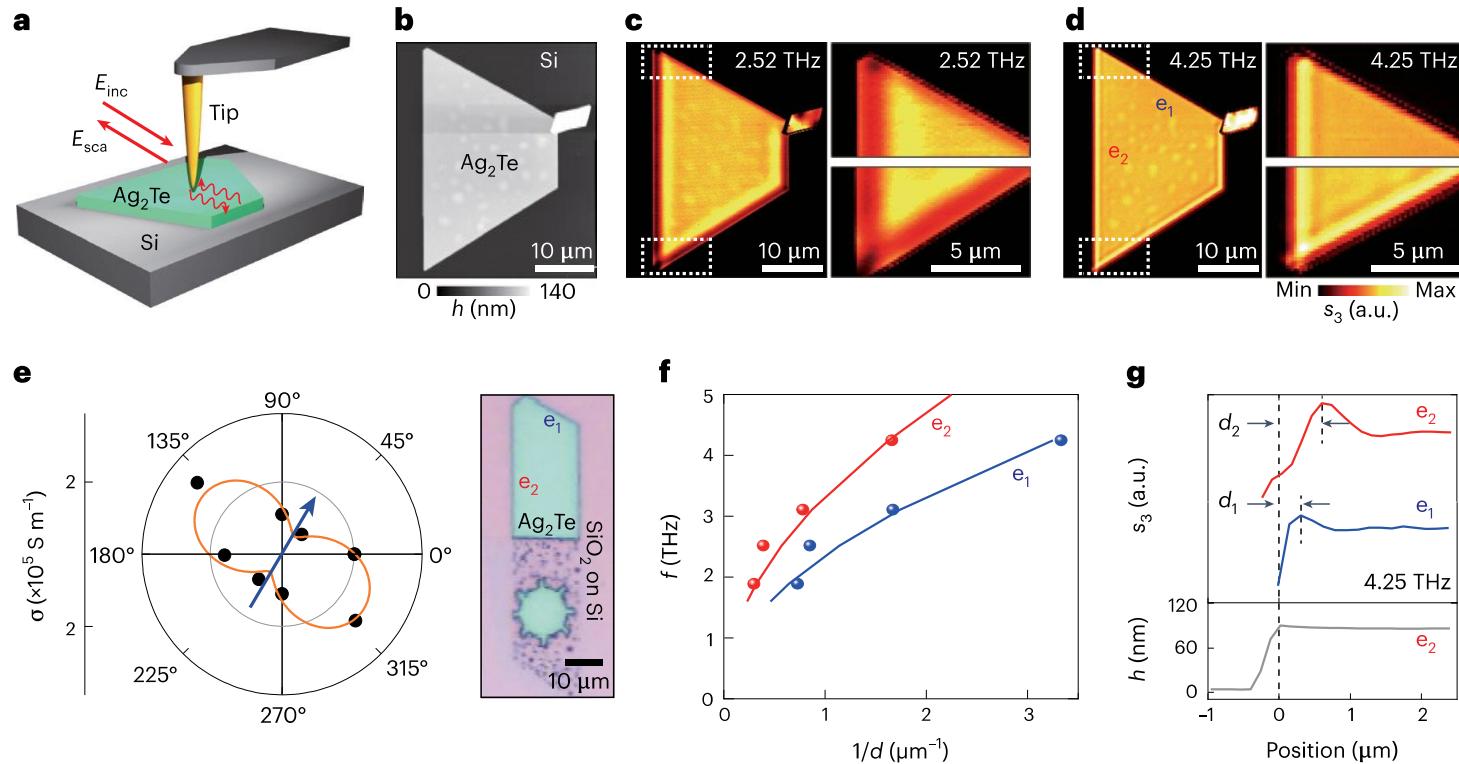
$$R = \frac{(n-1)^2 + \kappa^2}{(n+1)^2 + \kappa^2}$$

absorption

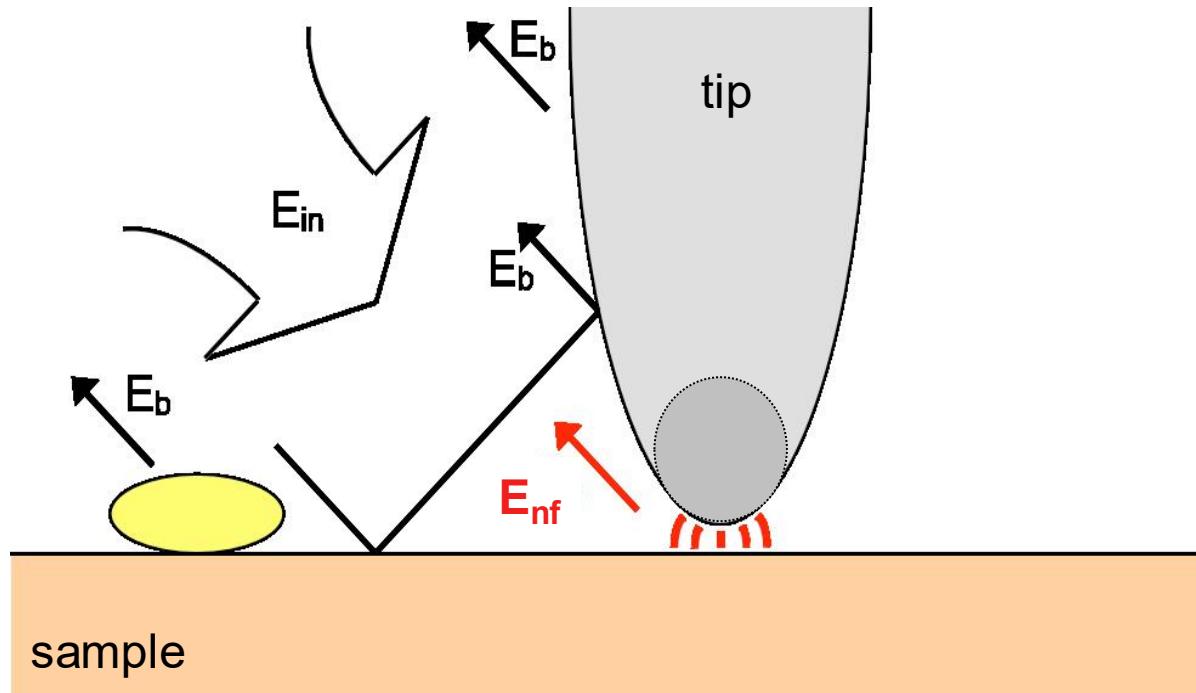
$$\gamma = \frac{4\pi\kappa}{\lambda}$$



# THz plasmon polaritons in a Ag<sub>2</sub>Te slab



# Scattering sources

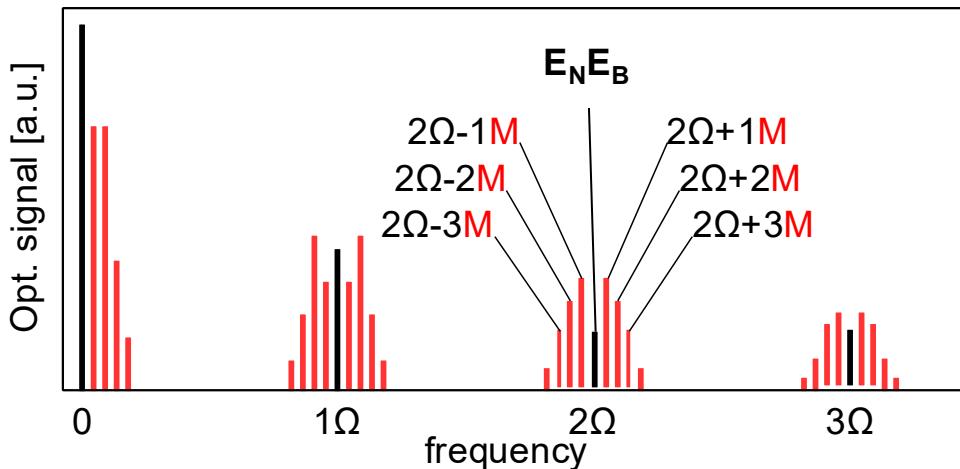
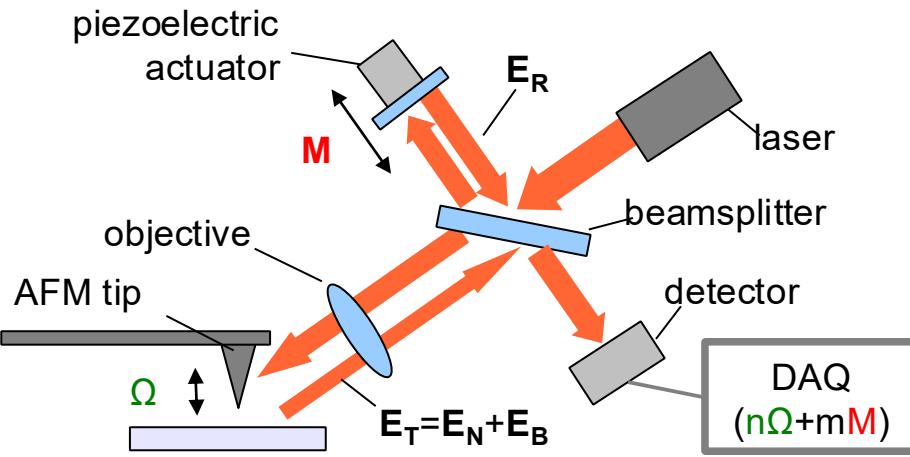


$E_{in}$  : incident light

$E_{nf}$  : scattered light of near-field interaction

$E_b$  : background scattered light

# Pseudo-heterodyne detection for simultaneous amplitude and phase mapping



- Additional modulation of reference mirror with frequency  $M$  (amplitude ca.  $0.21\lambda$ ) => generation of sidebands
- Sidebands are used to calculate near-field amplitude and phase

$$s_n \propto \sqrt{|U_{n\Omega+M}|^2 + |U_{n\Omega+2M}|^2}$$

$$\phi_n = \tan^{-1} \frac{|U_{n\Omega+M}|}{|U_{n\Omega+2M}|}$$

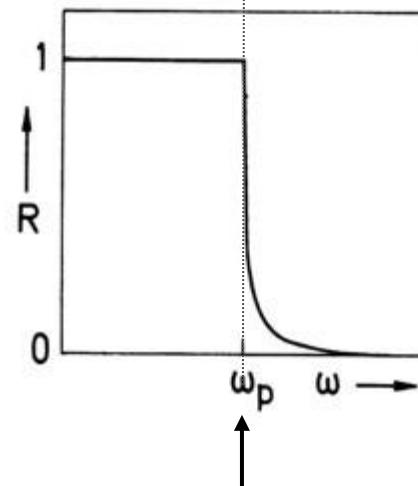
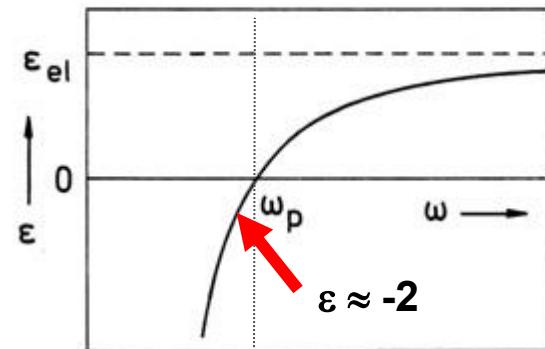
- Features:
  - broad spectral range
  - any coherent source
  - sequential spectroscopy
- Fast data acquisition

# Dielectric function of metals and polar crystals



## Metals / doped semiconductors

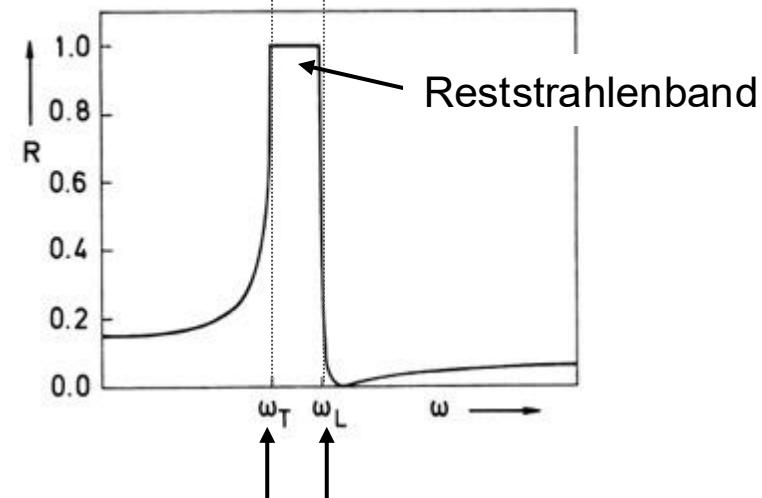
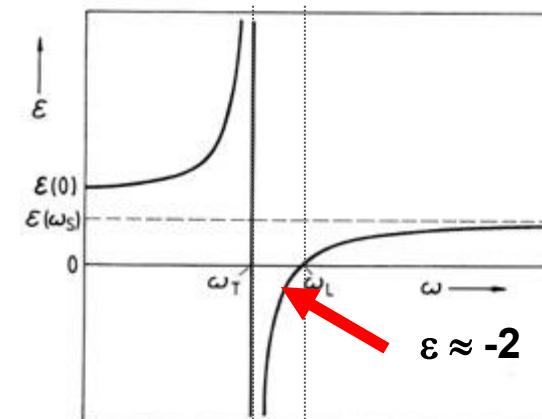
collective free electron oscillations (plasmons)



plasma frequency  
(longitudinal oscillation)

## Polar crystals

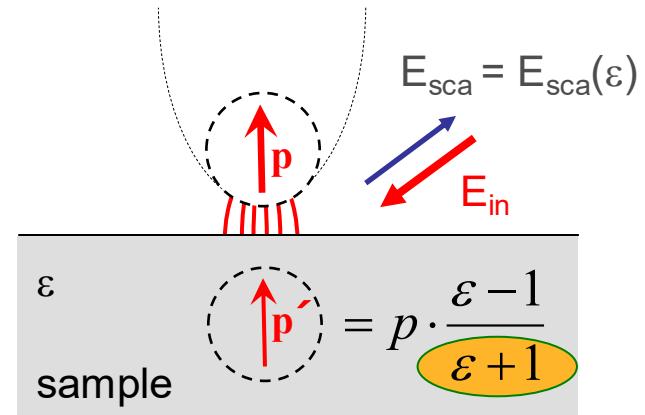
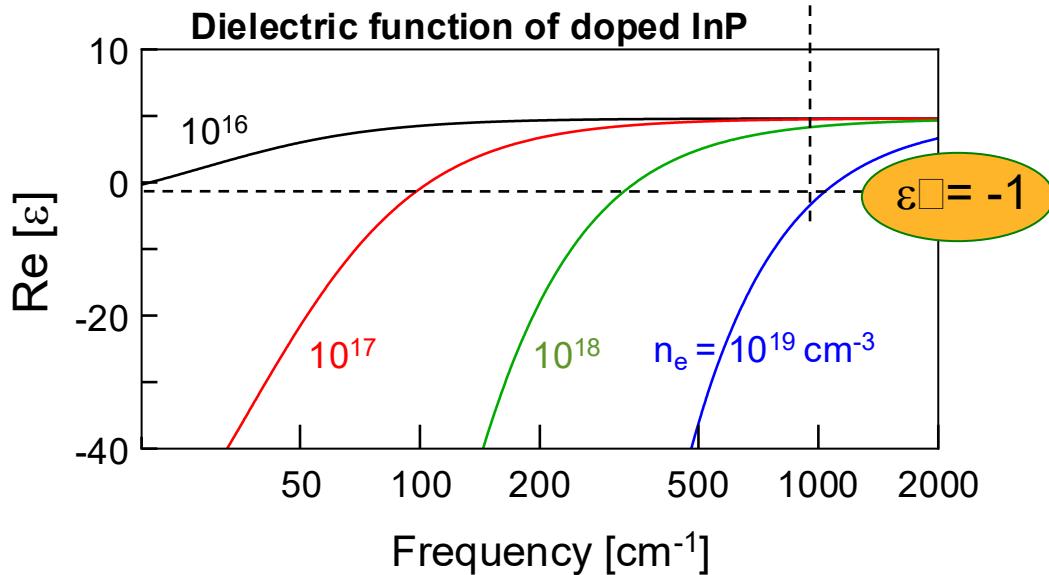
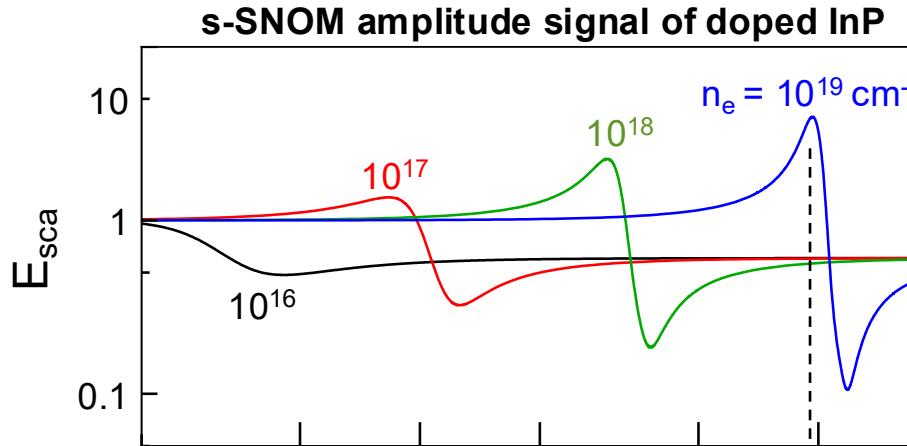
strong lattice vibrations (phonons)



transversal optical  
phonon frequency, TO

longitudinal optical  
phonon frequency, LO

# Near fields at the tip apex induce a local plasmon resonance in semiconductor samples



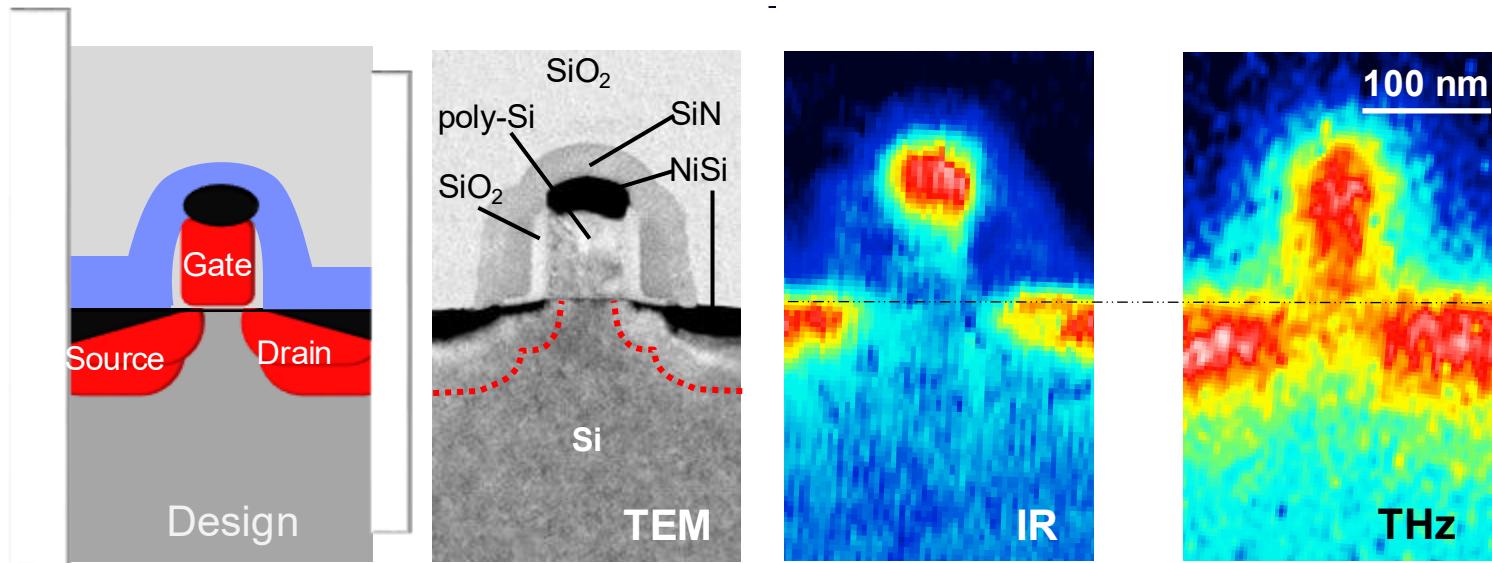
Dielectric function  $\epsilon(\omega)$  is determined by plasma frequency  $\omega_P$  and damping  $\gamma$ :

$$\epsilon(\omega) = \epsilon_{\infty} \left( 1 - \frac{\omega_P^2}{\omega^2 + i\gamma\omega} \right)$$

with

$$\omega_P^2 = \frac{n_e e^2}{\epsilon_0 \epsilon_{\infty} m \cdot m_0}$$

# THz s-SNOM reveals free carriers in single 65-nm-transistor



█ highly doped Si,  $n = 10^{19} \text{ cm}^{-3}$

For doped silicon  $\epsilon(\omega)$  depends on the free-carrier concentration  $n$ :

$$\epsilon(\omega) = \epsilon_0 \left[ 1 - \frac{\omega_p^2}{\omega^2 + i\gamma\omega} \right]$$

with  $\omega_p^2 = \frac{n e^2}{\epsilon_0 \epsilon_s m m_0}$

